

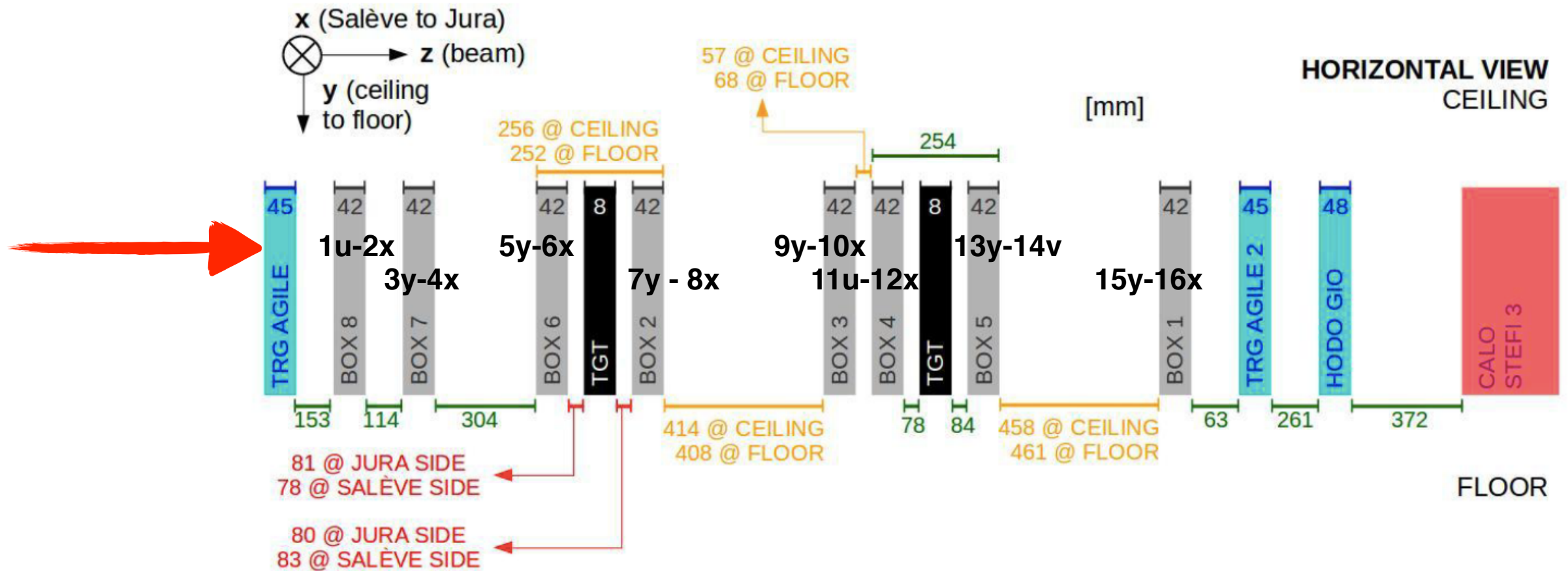
Summary on alignment test beam 2018

**MUonE meeting
04/12/2018**

A. Principe

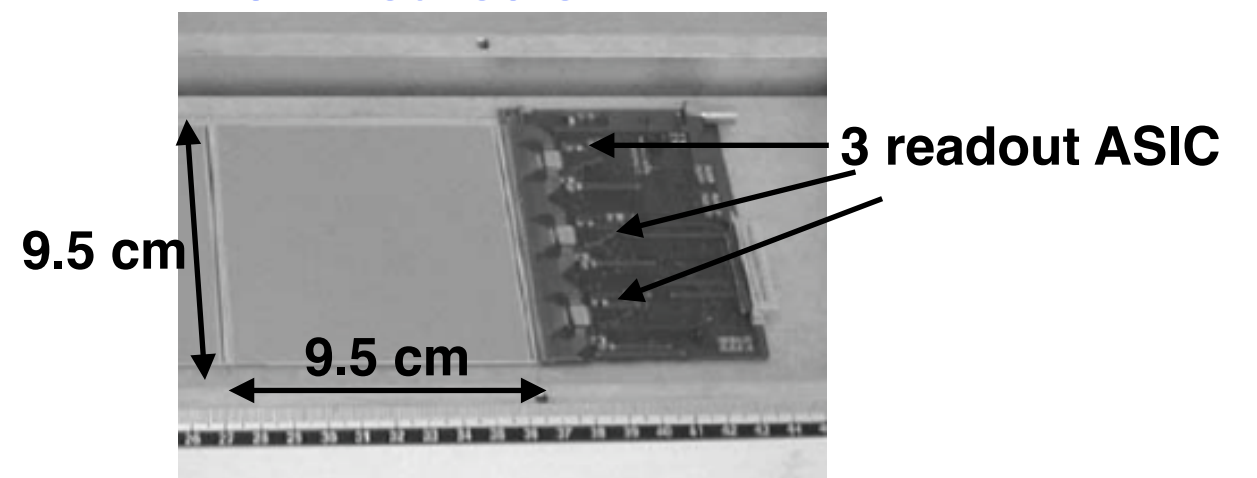
Test beam apparatus

MUonE configuration @ 02/05



- Strip pitch: 242 μm
- Nominal point resolution $\sim 35\text{-}40 \mu\text{m}$
- from 4/05: 3 upstream boxes
- from 27/06: no target 2
- from 20/08: new box 8 and 3

AGILE sensors



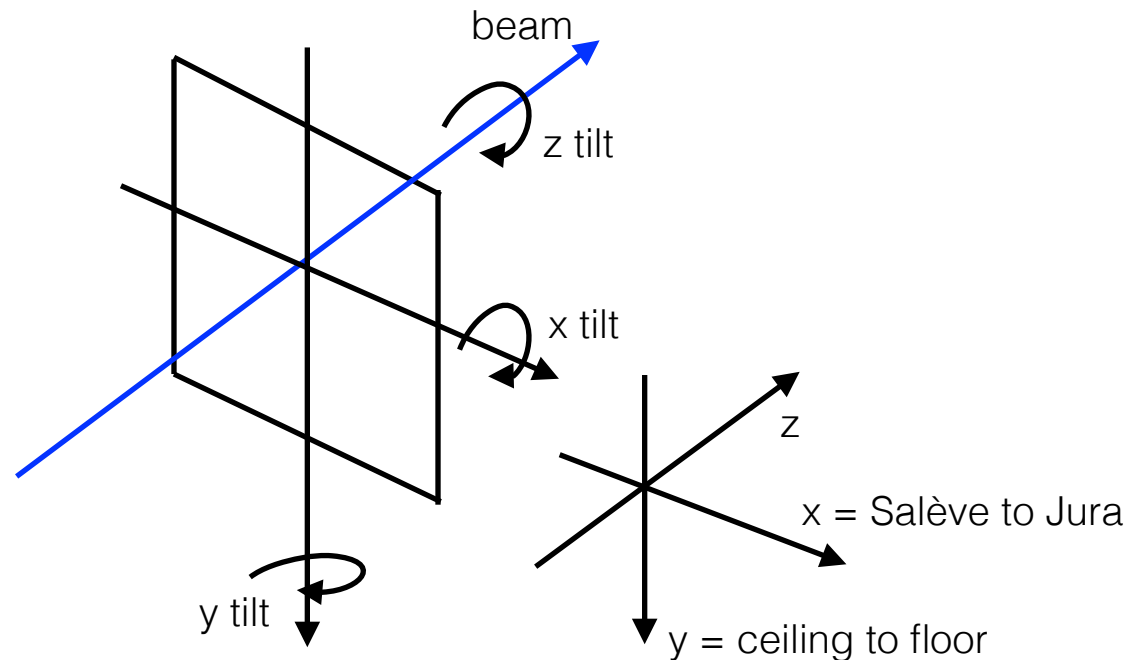
Alignment procedure

- We have chosen an histogram-based procedure suitable for small apparatus, like test beams: with some changes, we have adapted the algorithm used for the test beam 2017.

$$hits'_i = hits_i - r_i - a_i \cdot hits_j$$

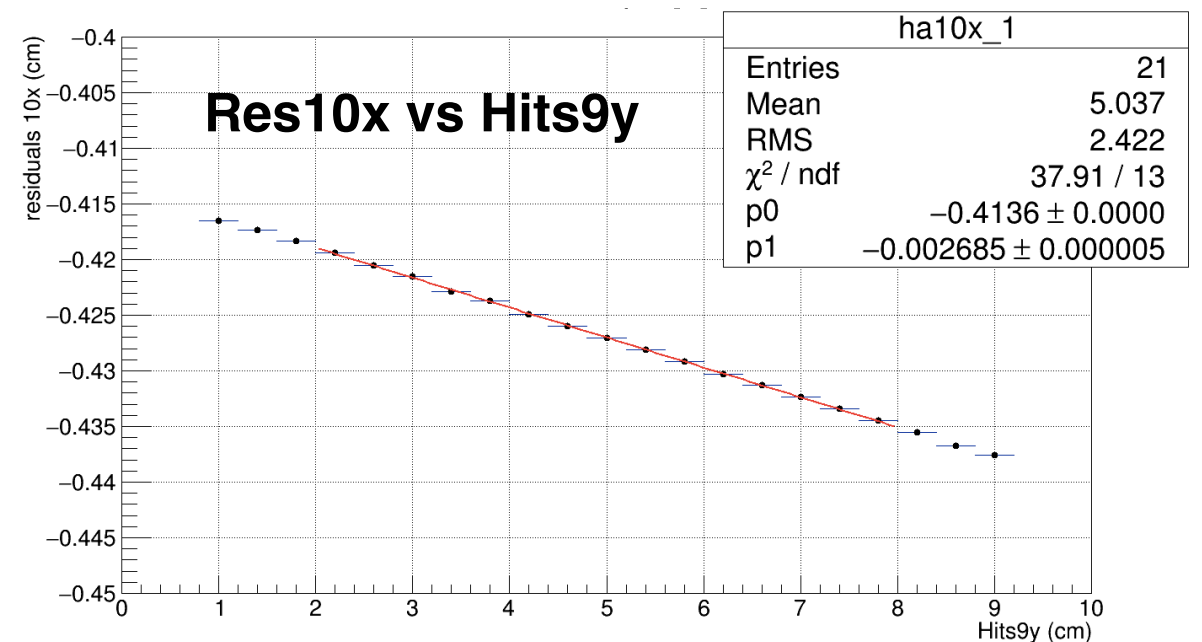
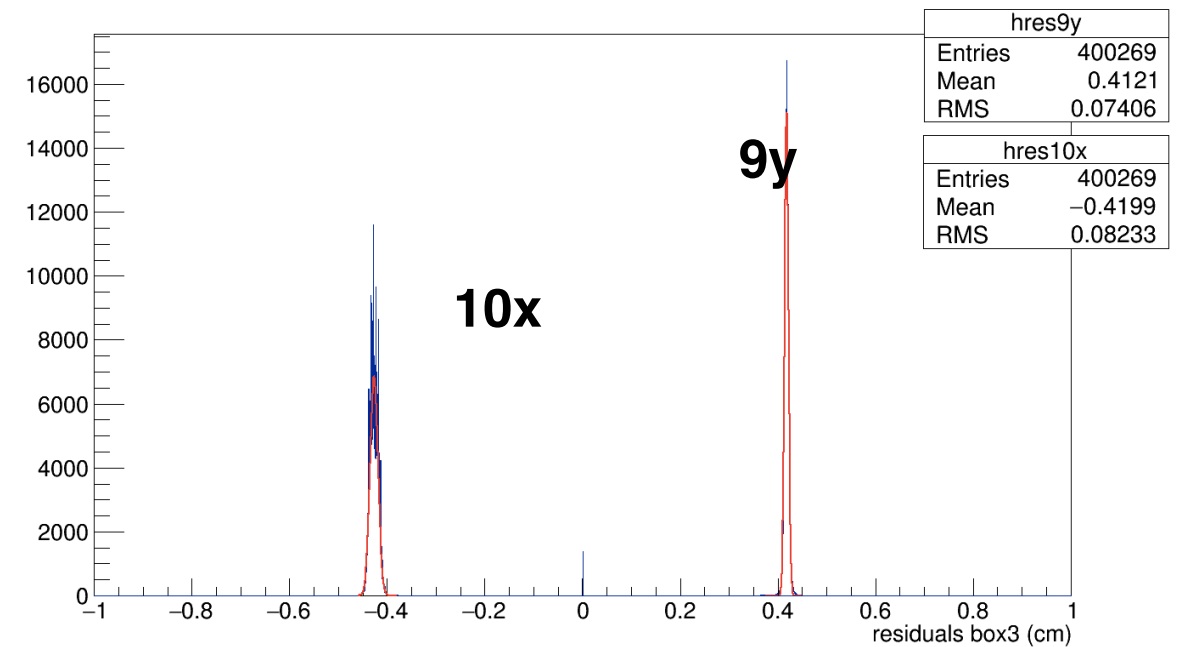
$$\Rightarrow r_i \text{ from } res_i$$

$$\Rightarrow a_i \text{ from } res_i \text{ vs } hits_j$$

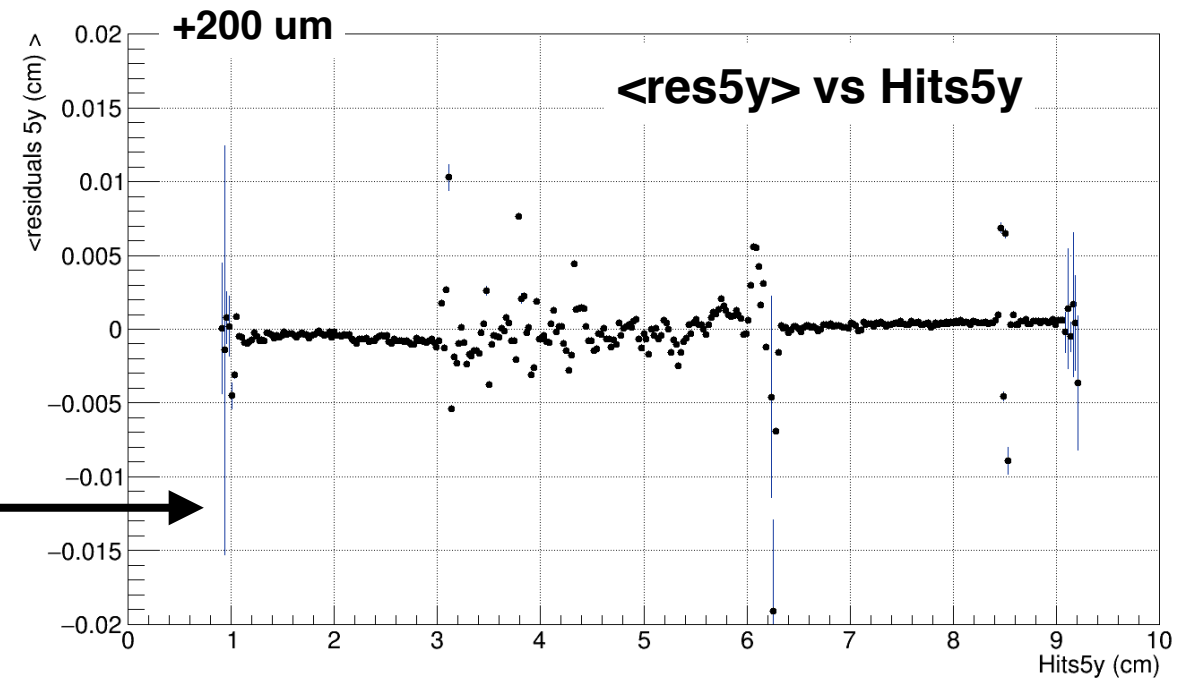
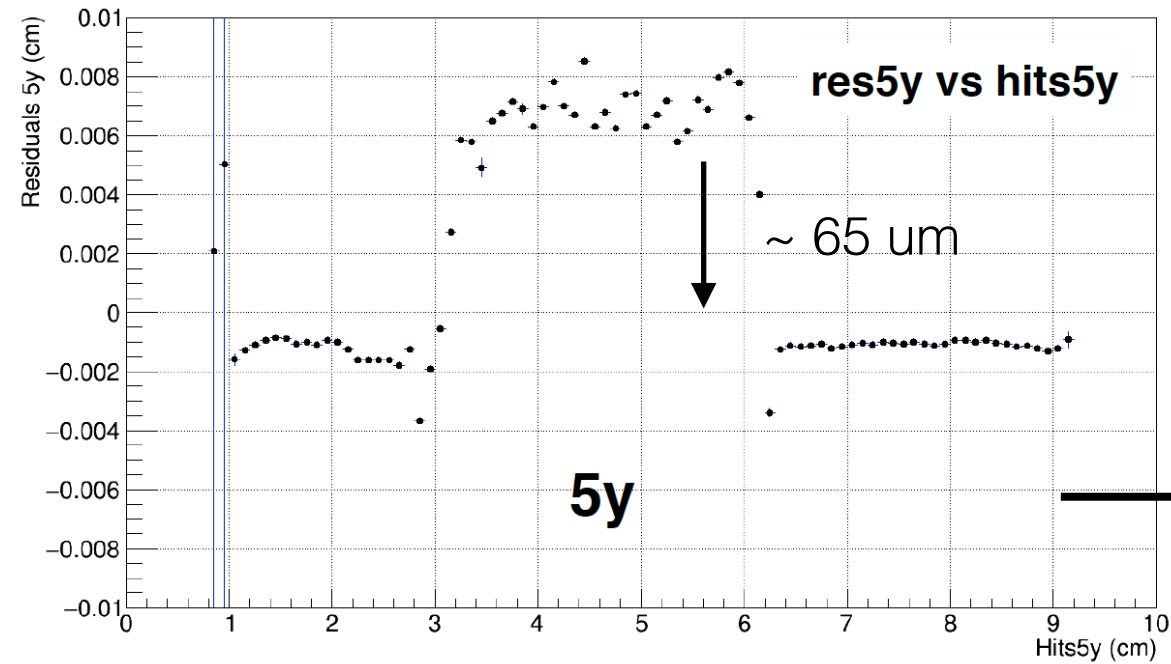


- This procedure is **iterative** and can only converge if two layers per view are chosen as references.
- This is a drawback, as we have seen that all layers have more or less some misalignments.
- Only a posteriori it's possible to check the bias introduced by these reference planes (next slides).

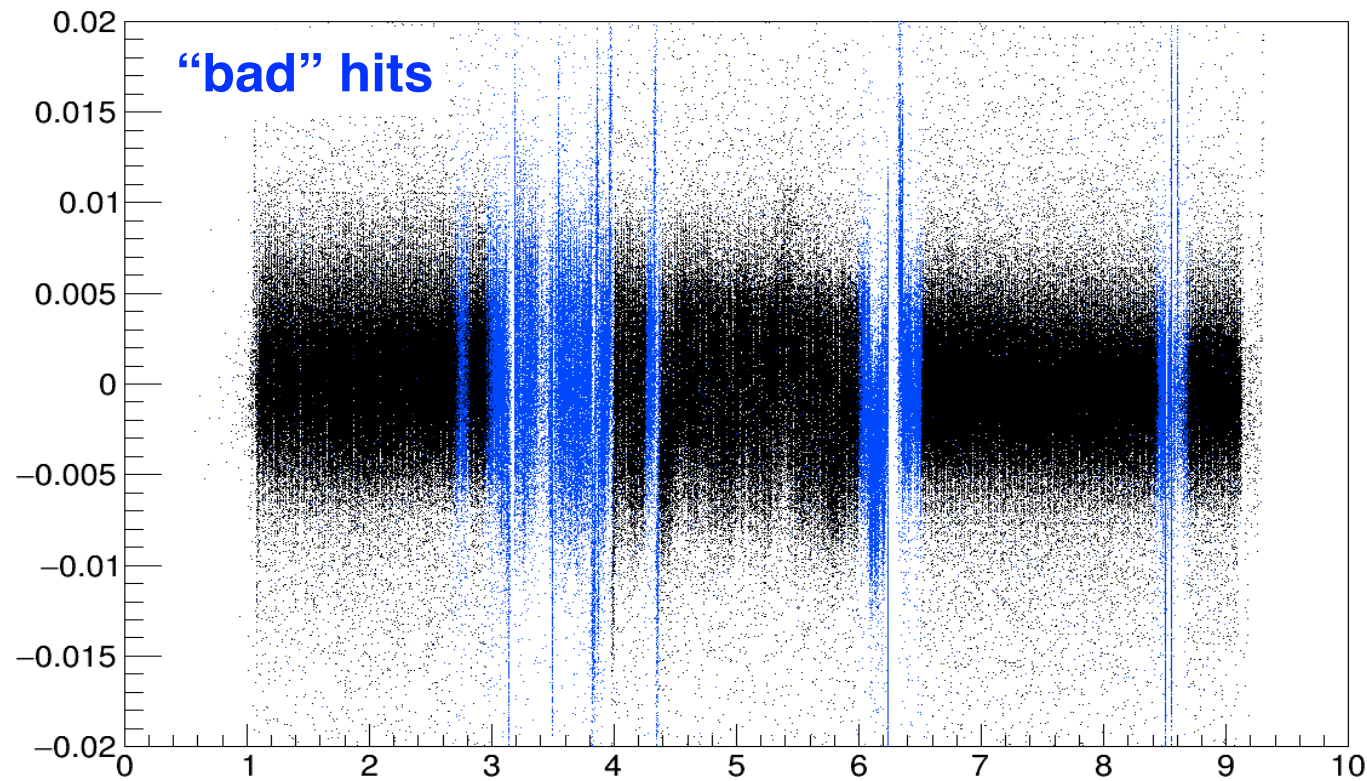
- With single muons along all apparatus:



Before alignment: example of layer problems

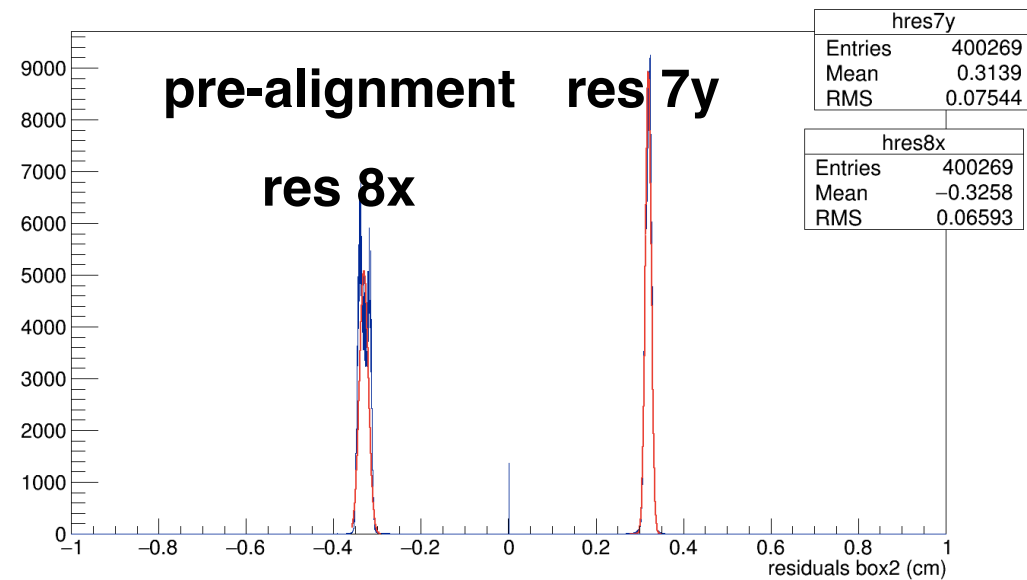


res7y:Hits7y

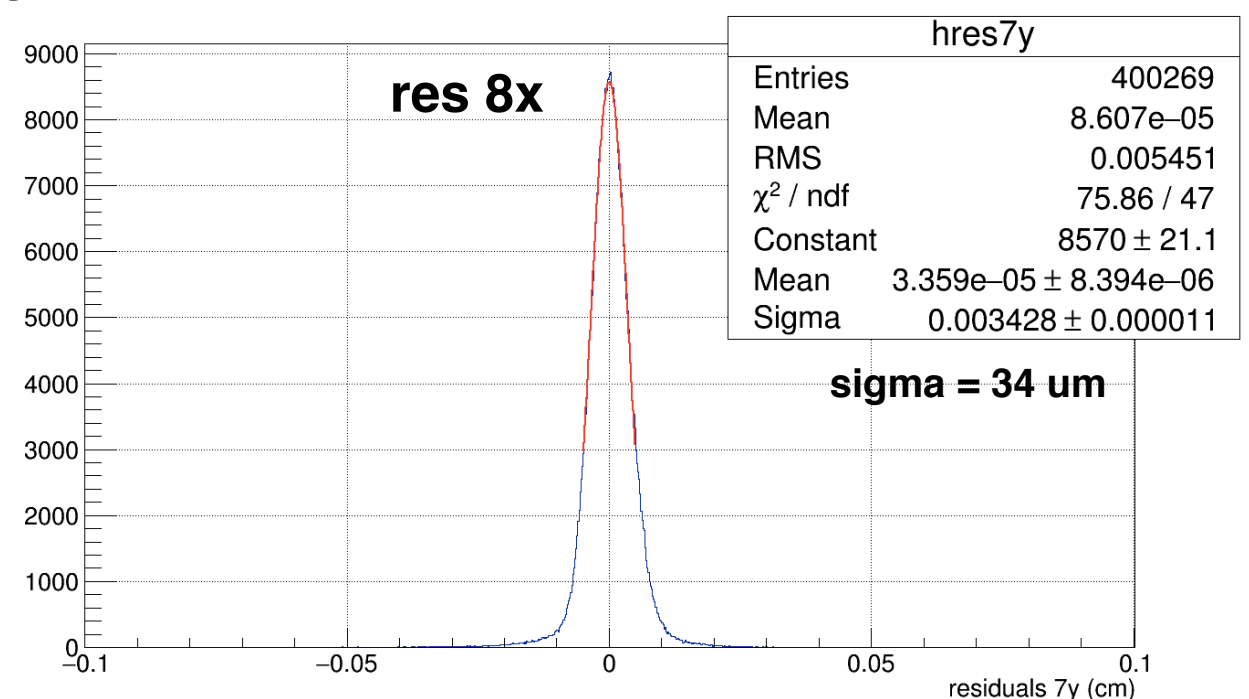
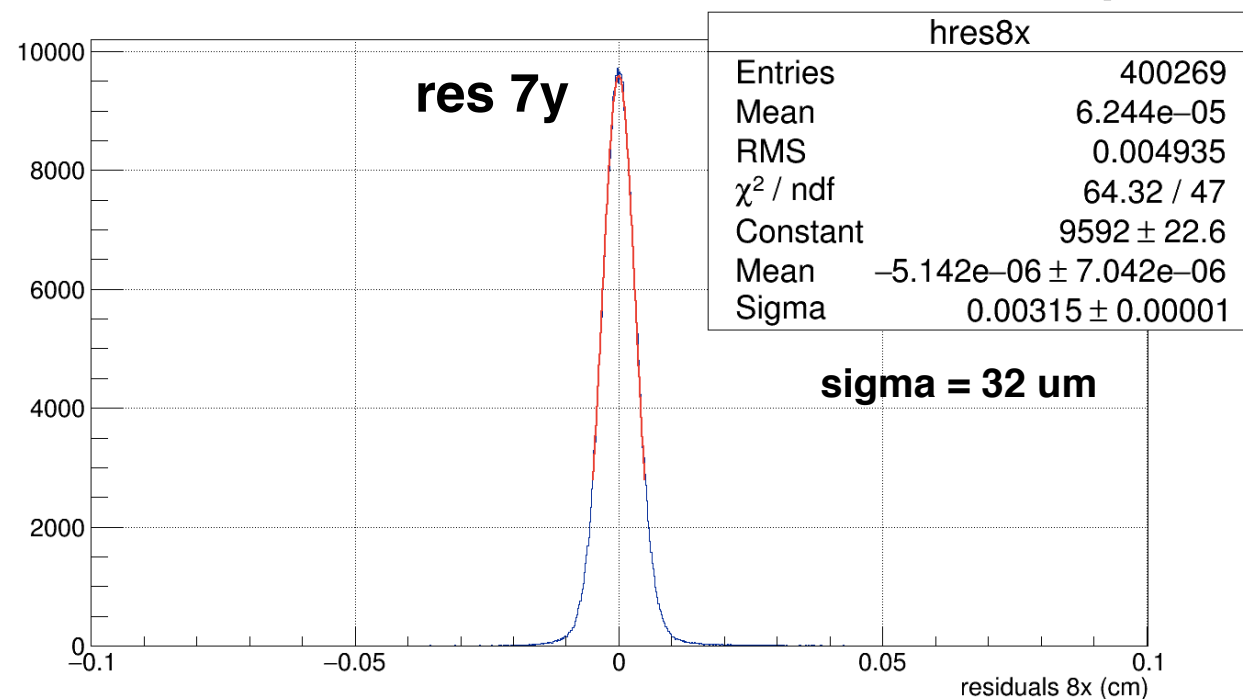


- Systematic readout shifts of layer 5y ($\sim 65 \mu\text{m}$) and 3y ($\sim 21 \mu\text{m}$) were corrected in analysis.
- Dead strips and nearest strips were masked, layer per layer.

x / y shifts and intrinsic resolution



- From residual distributions can be disentangled multiple scattering effect and point silicon resolution: in this case, as a first approximation (\rightarrow 180-190 GeV muons), residuals sigma can be considered the intrinsic resolution of silicon trackers.



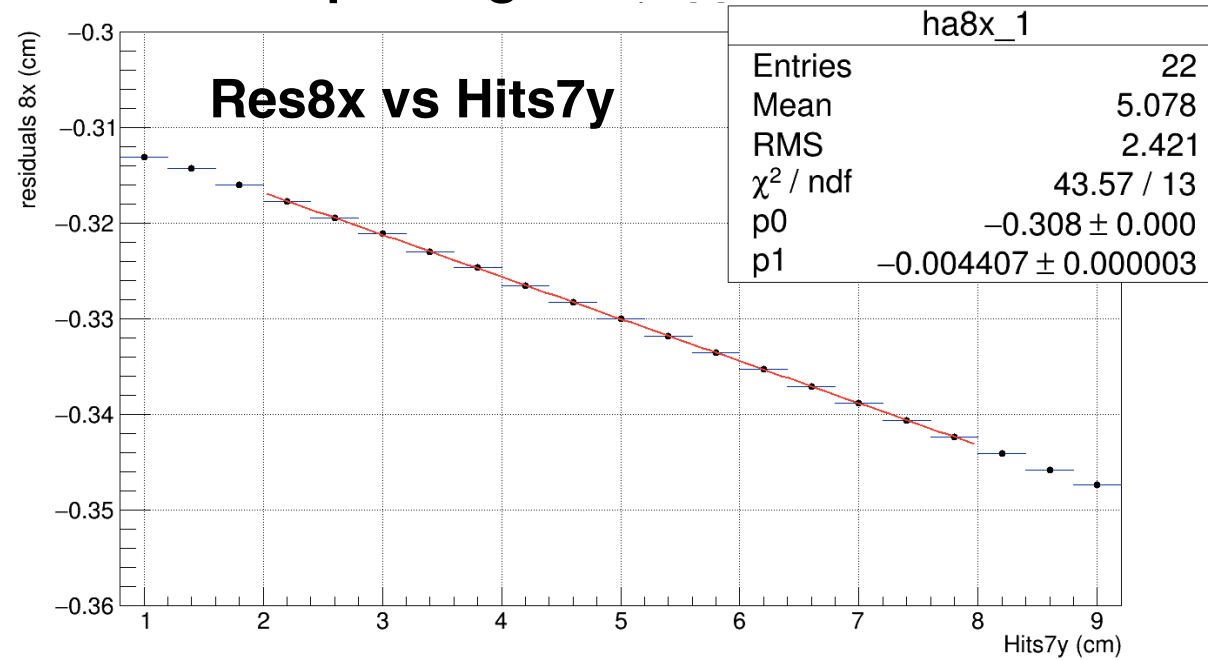
- A position resolution of roughly 37-47 micron is indicated as a reference in (1).
- AGILE readout strip pitch: **242 um** with “floating strip” (2).
- So geometrical tracker resolution is: $242/2 / \sqrt{12} = \mathbf{34.9 \text{ micron}}$. \longrightarrow After refinements, some sigma < 30 um: **26 / 25 um** for 7y / 8x (next slides).

! (1) https://www.Infn.infn.it/acceleratori/public/BTF_user/AGILE/nima490agile.pdf

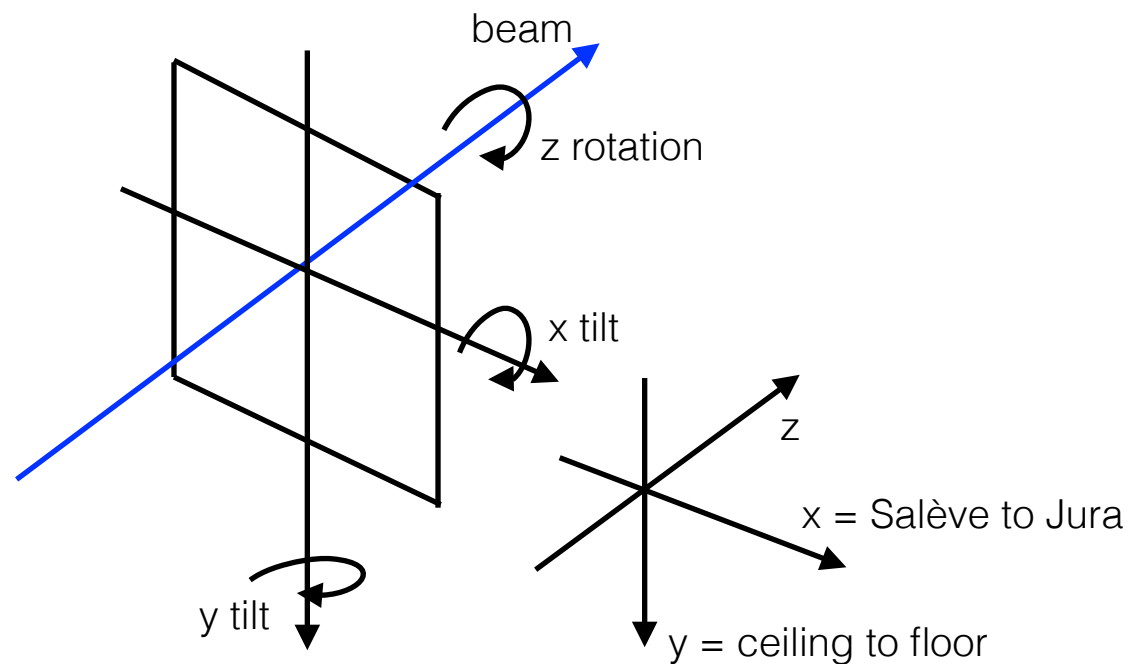
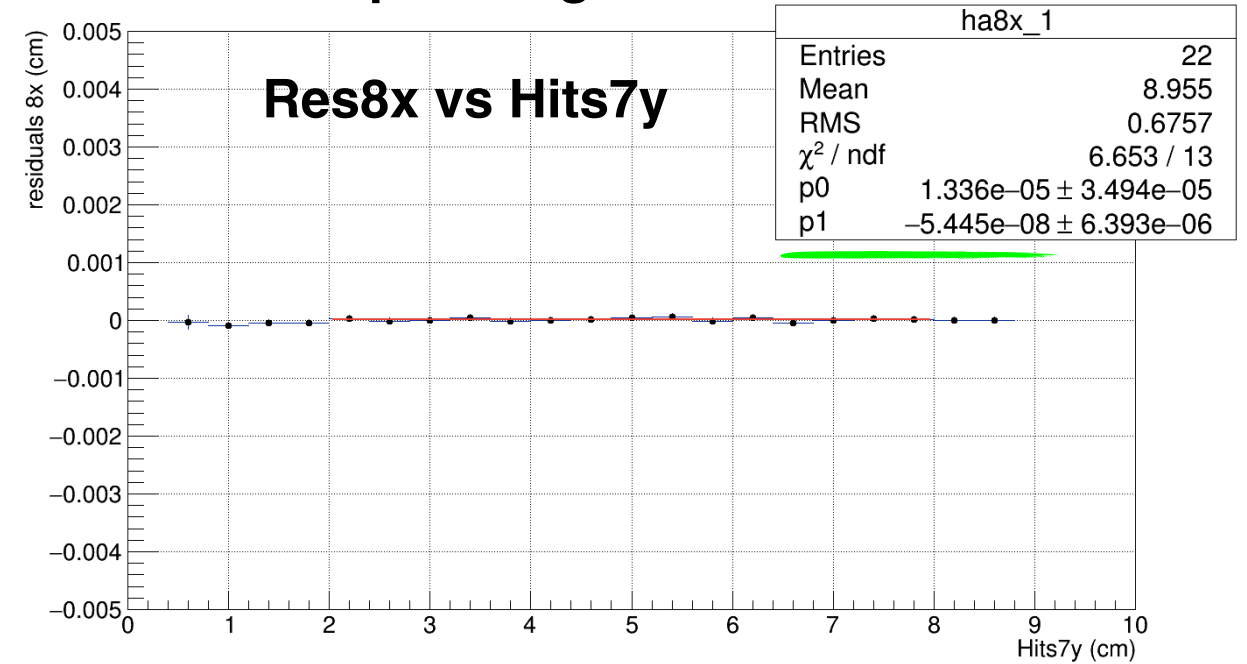
! (2) https://www.Infn.infn.it/acceleratori/public/BTF_user/AGILE/nima501agile.pdf

z rotations

pre-alignment



post-alignment

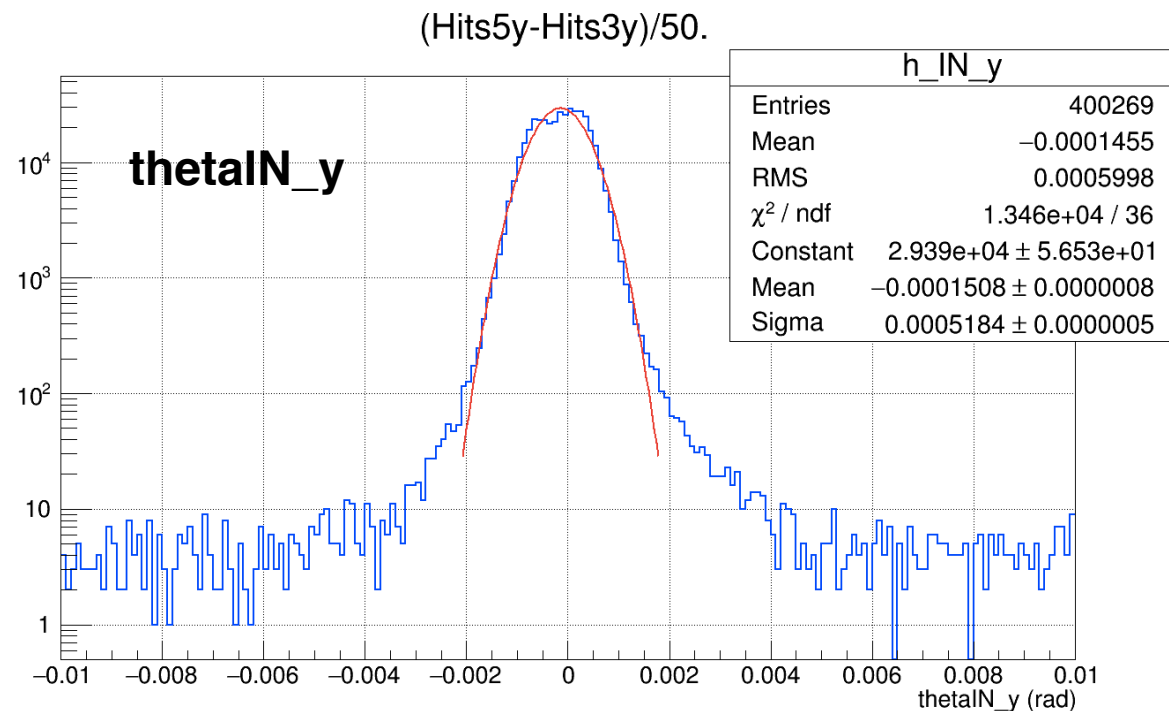
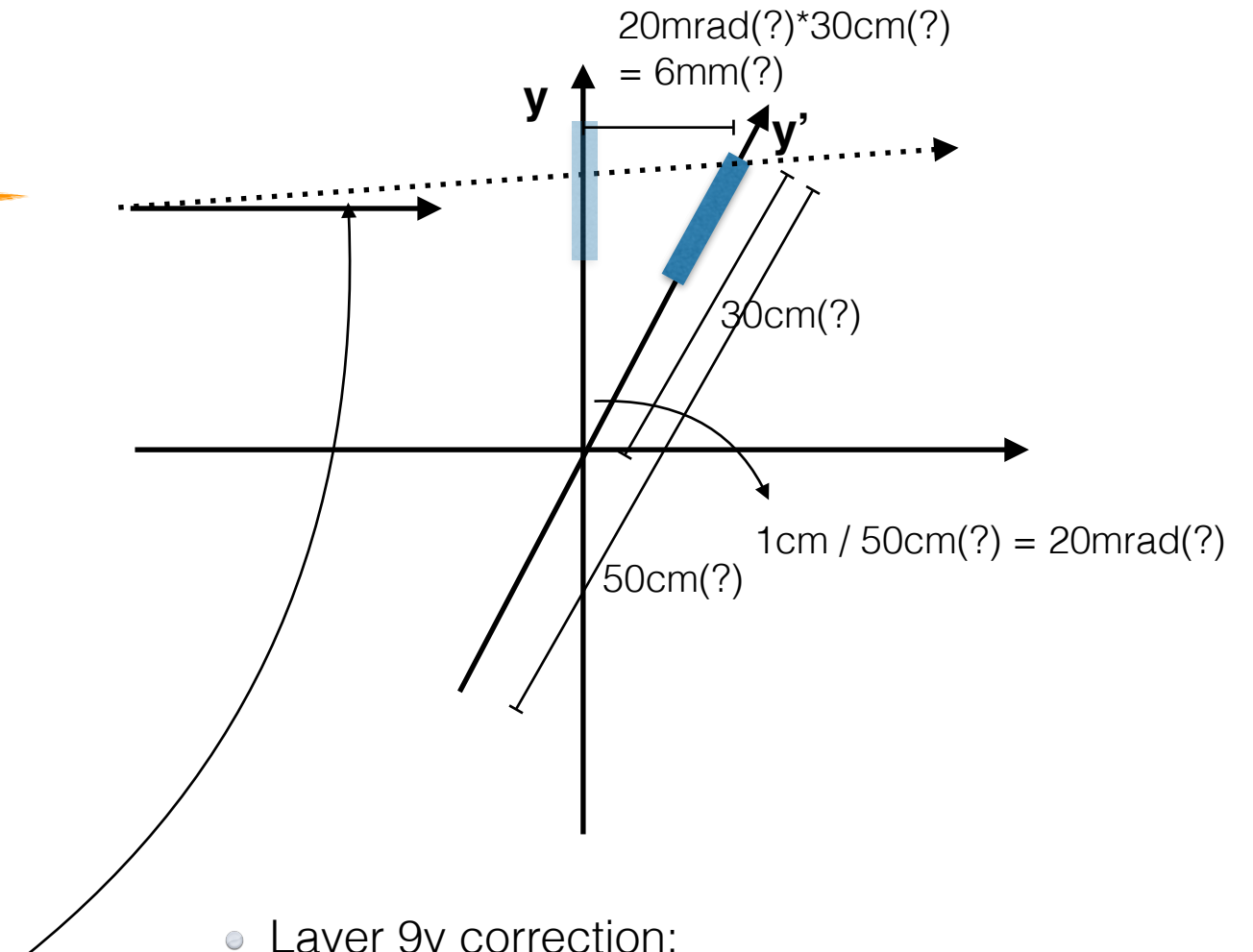
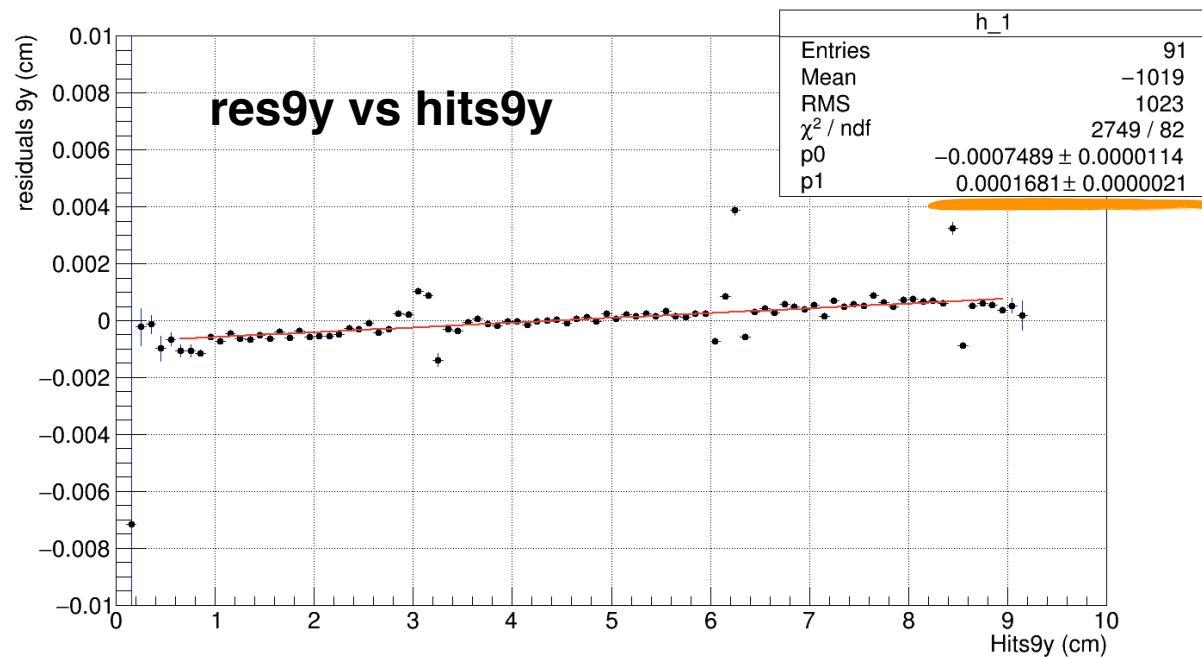


Alignment summary

- shifts in x / y **< 5 mm** corrected within 1 μm .
- rotations along z axis **< 5-6 mrad**, corrected within 0.1 mrad.

Tilt correction

- We have some sensibility also on tilts (rotations along y / x axis): second-order corrections.



- Layer 9y correction:

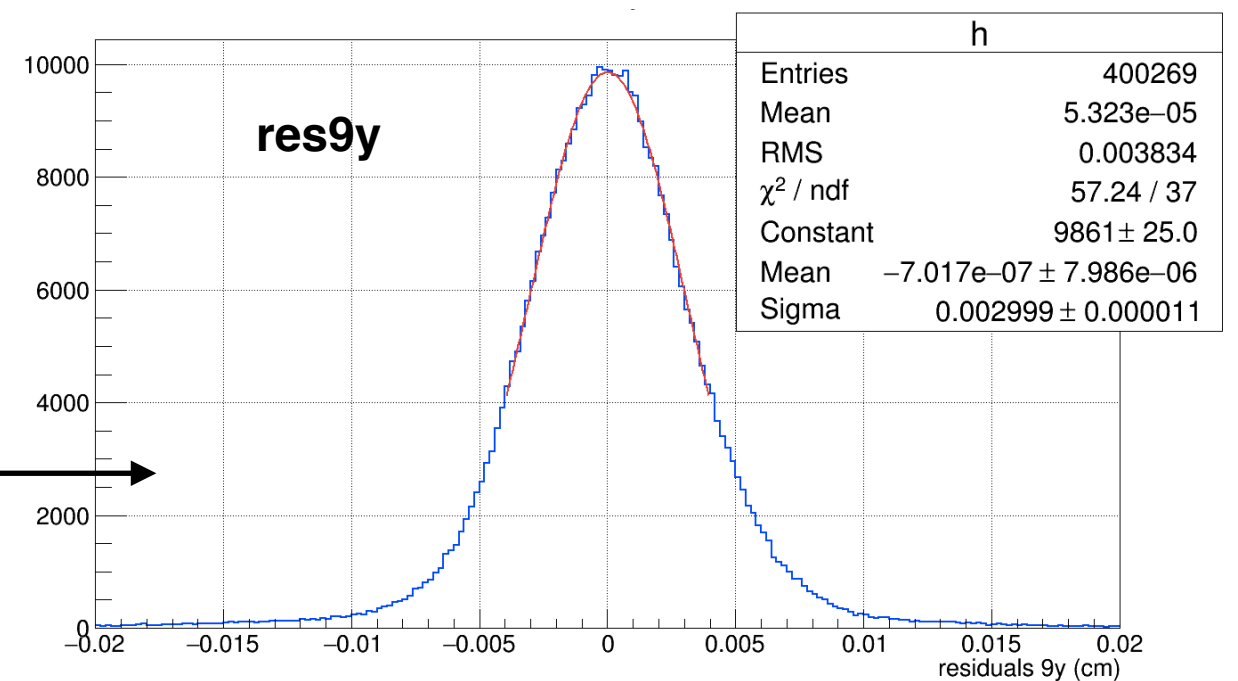
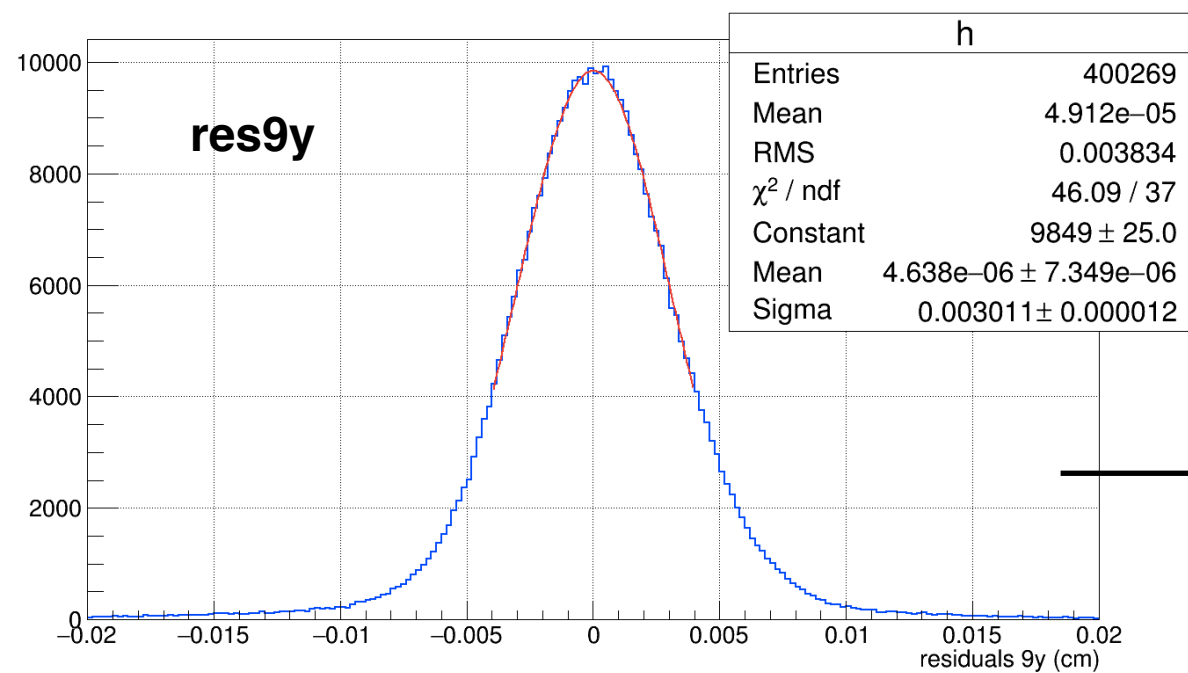
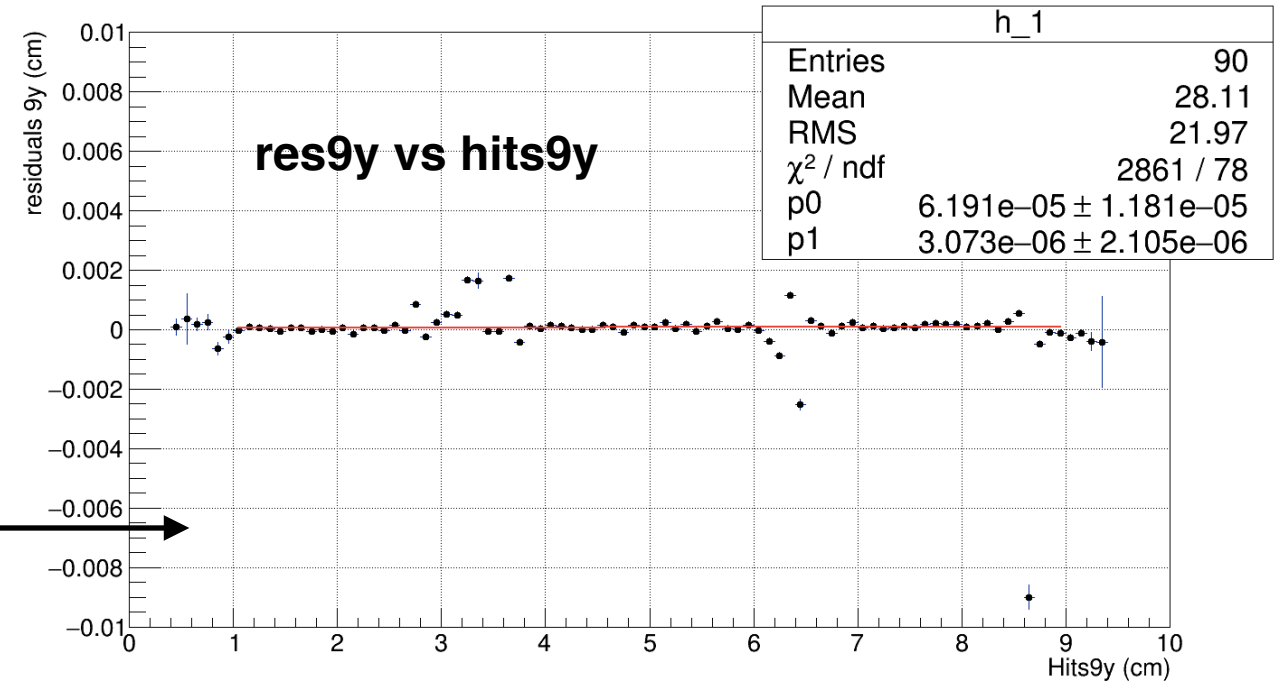
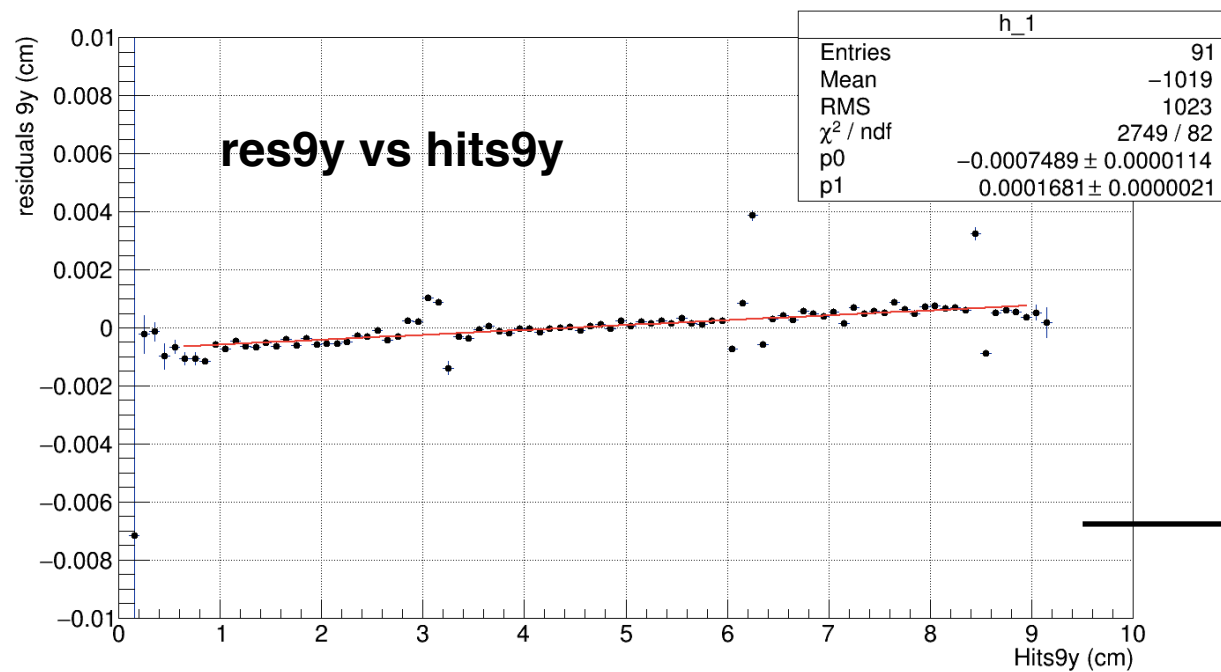
$$\text{hits9y}' = \cos\alpha * \text{hits9y}$$

$$\text{hits9y}' \sim (1 - \alpha^2/2) * \text{hits9y}$$

$$\alpha^2/2 = 0.00017 \rightarrow \alpha = 0.018 \text{ rad}$$

(This tilt angle deduced from correlation looks like compatible with layers distances).

Tilt correction of 9y



- The positive correlation disappears and small improvements on residual.
- Given the large amount of these rotations, it is not possible to correct them iteratively. We are outside the linearity of the corrections.

Stereo layers alignment

- residuals:**

$$res_i = hits_i - [\cos \beta (a_x z_i + b_x) - \sin \beta (a_y z_i + b_y)] + c_i$$

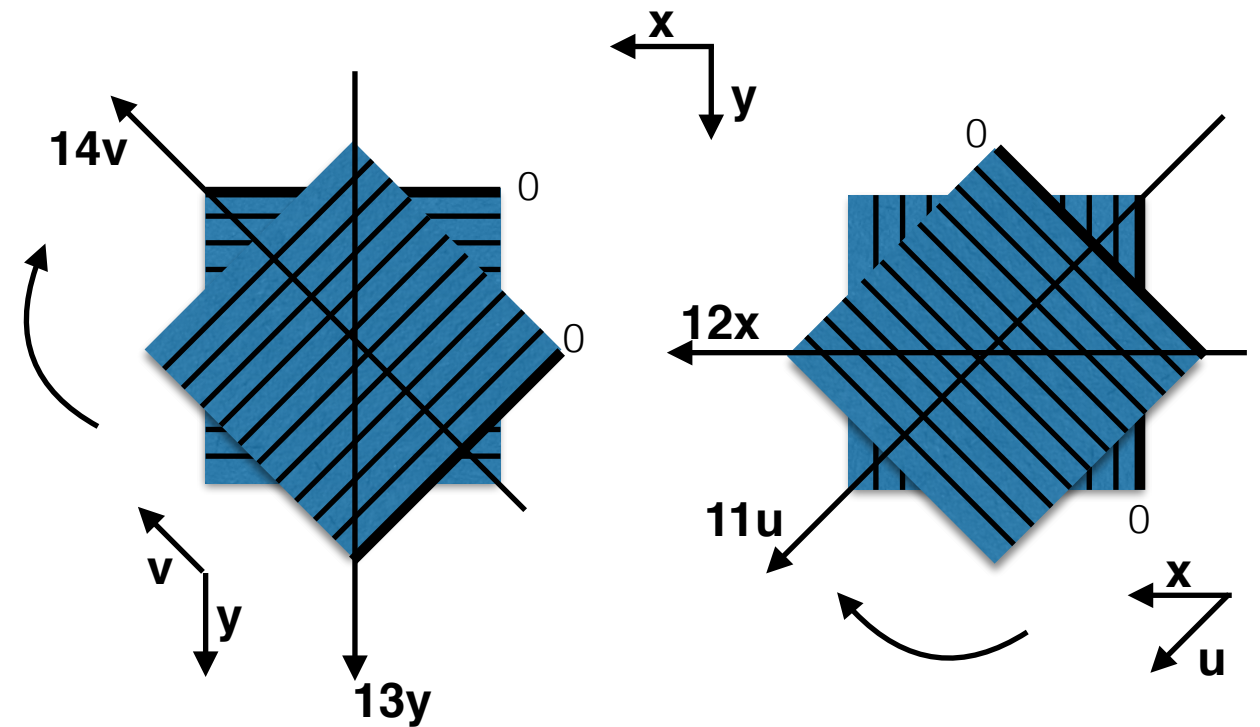
$$\beta = -\frac{\pi}{4} \quad \text{for} \quad i = 11u$$

$$\beta = +\frac{\pi}{4} \quad \text{for} \quad i = 14v$$

~~$$c_{11u} = 1.8036 \text{ cm}$$~~

~~$$c_{14v} = -5.1100 \text{ cm}$$~~

iteratively!



- alignment (in uv direction):**

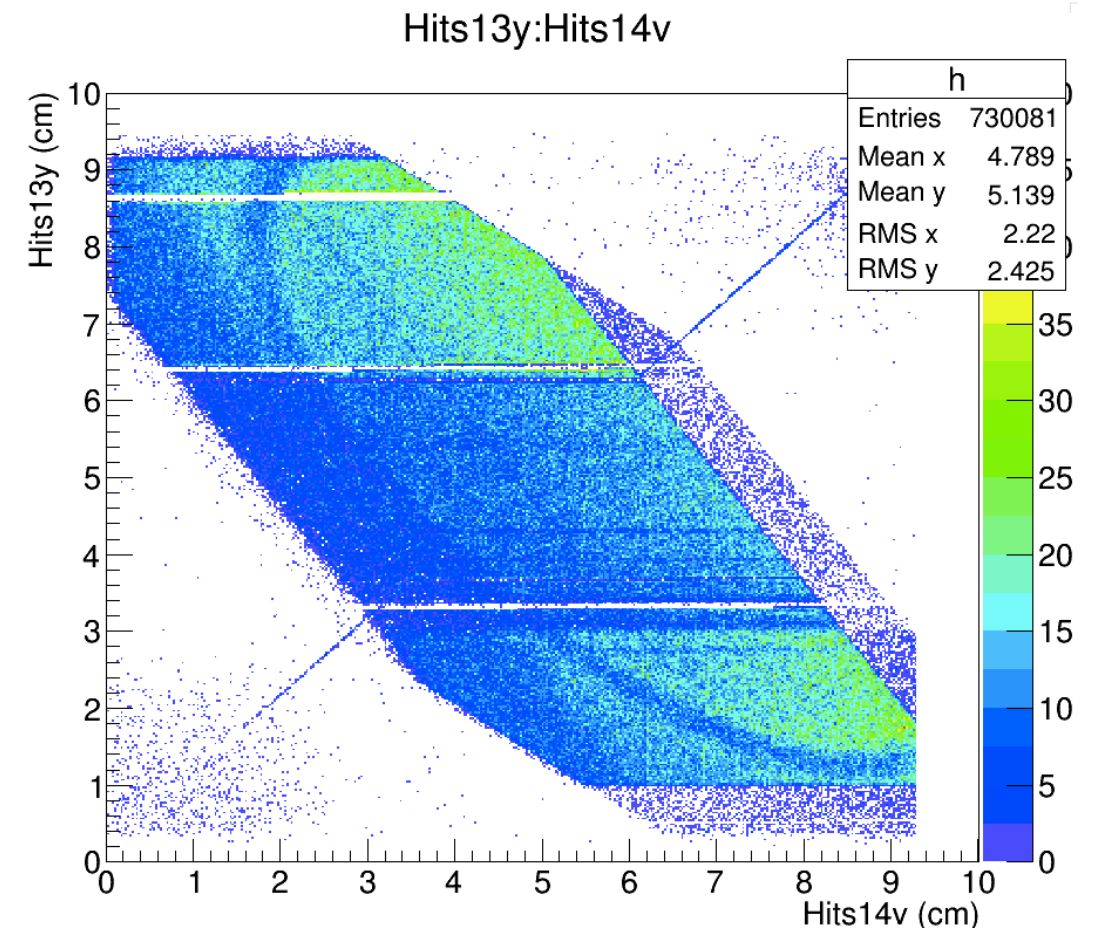
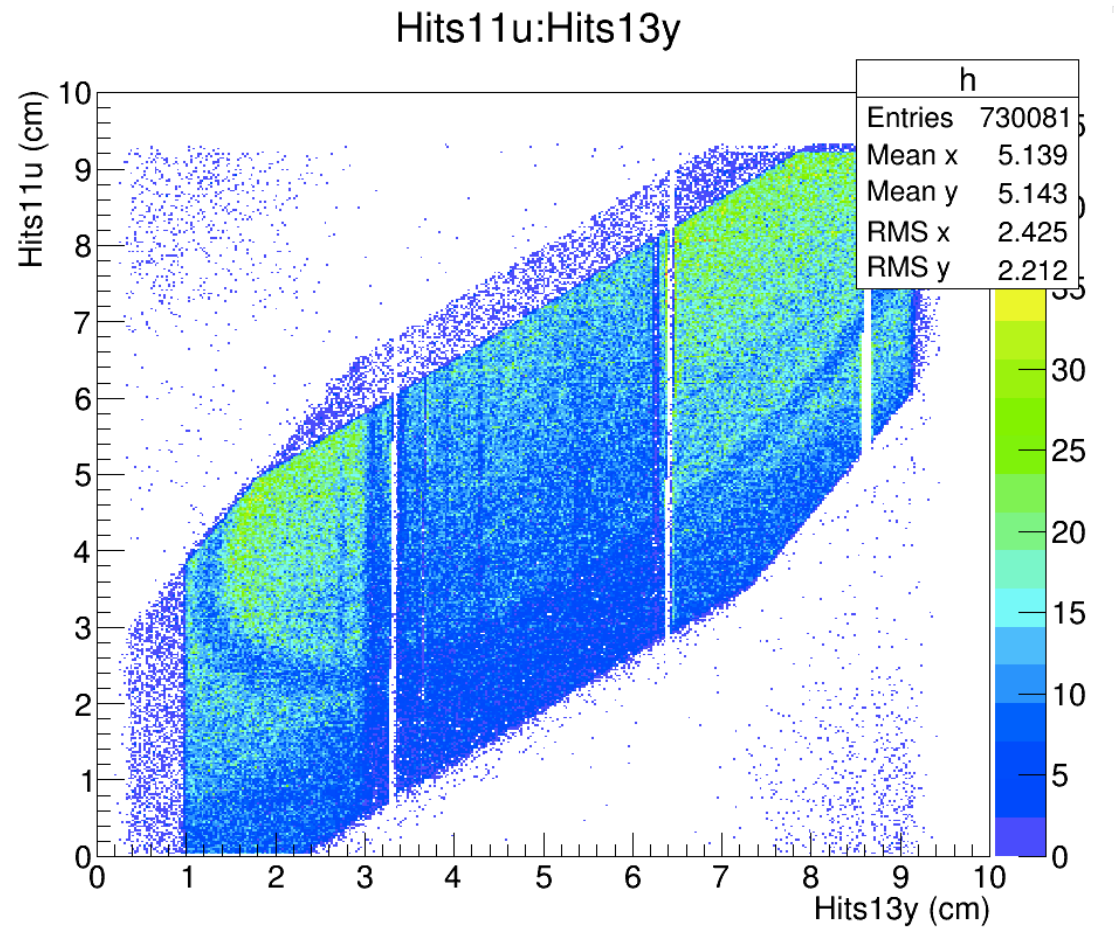
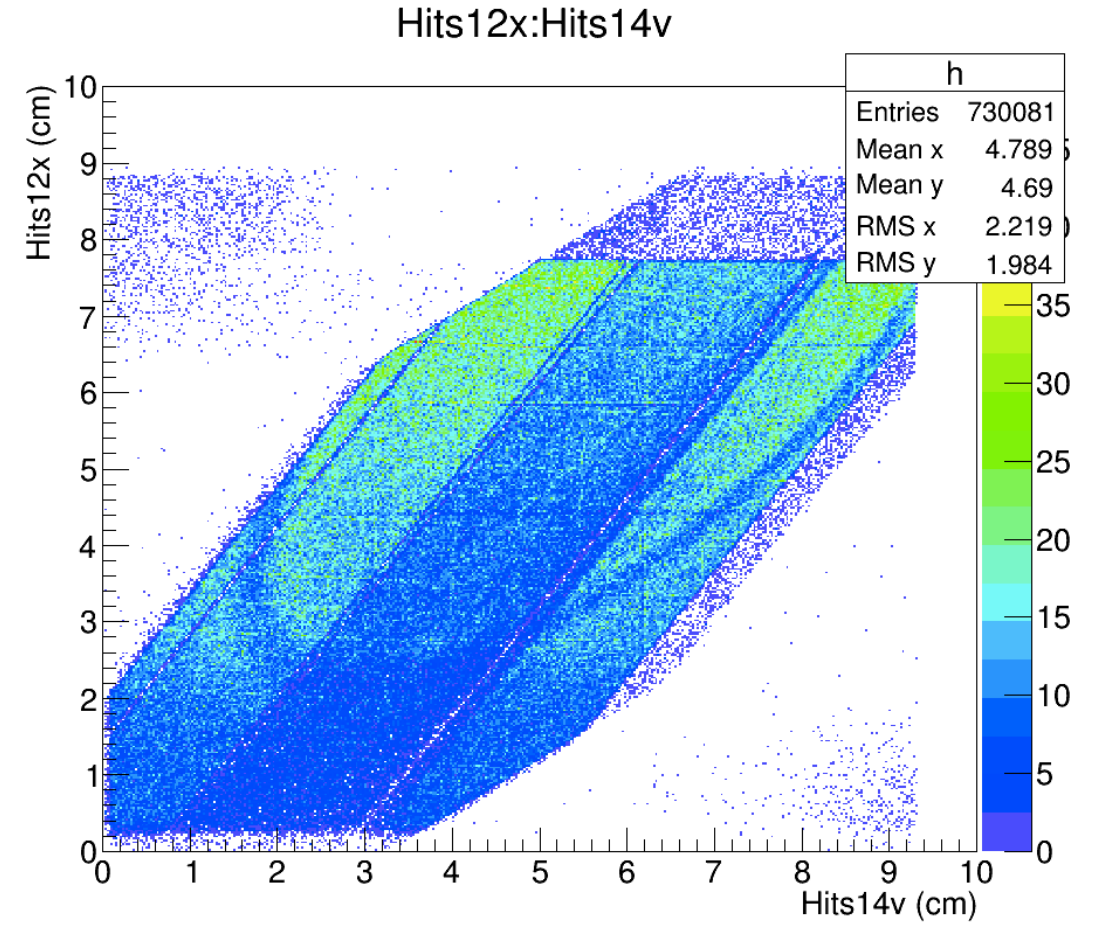
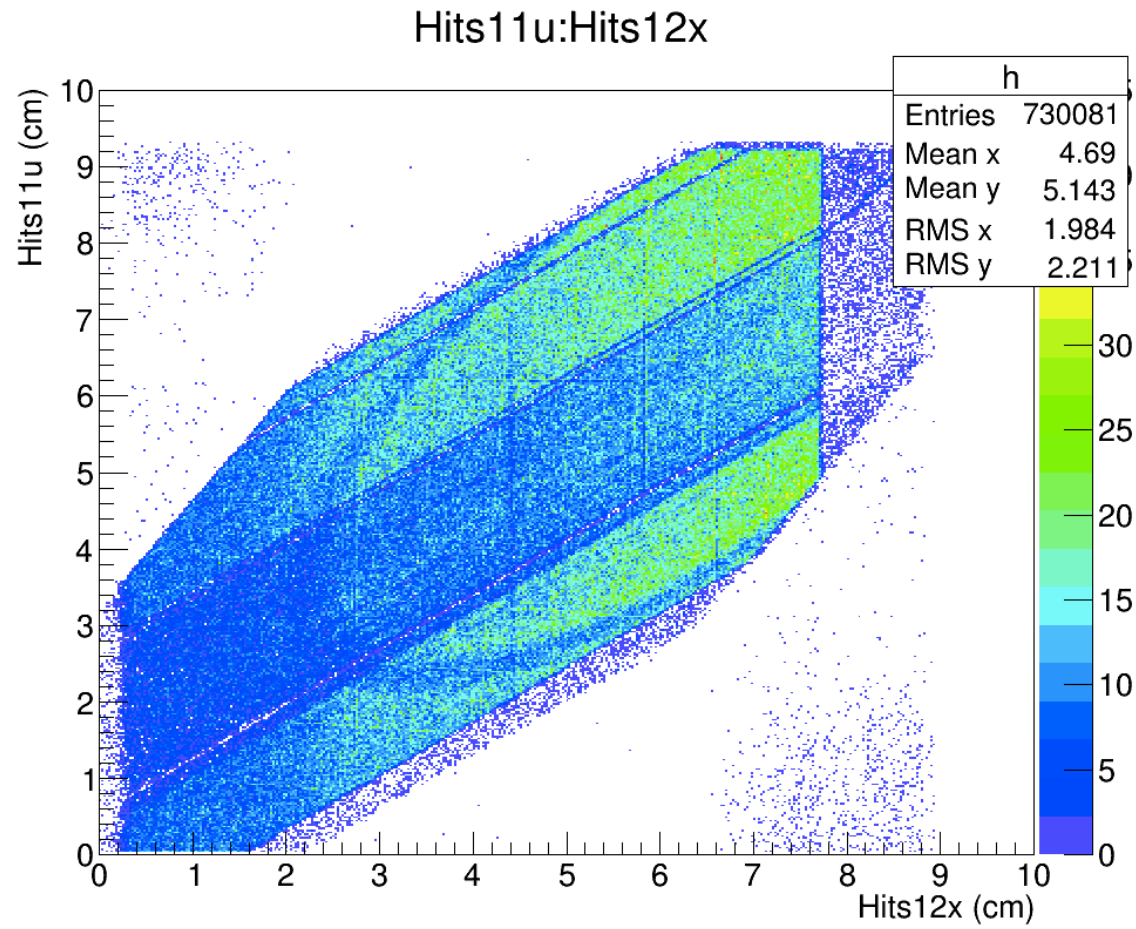
$$hits'_i = hits_i - r_i - a_i \cdot hits_j$$

$$\implies r_i \text{ from } res_i$$

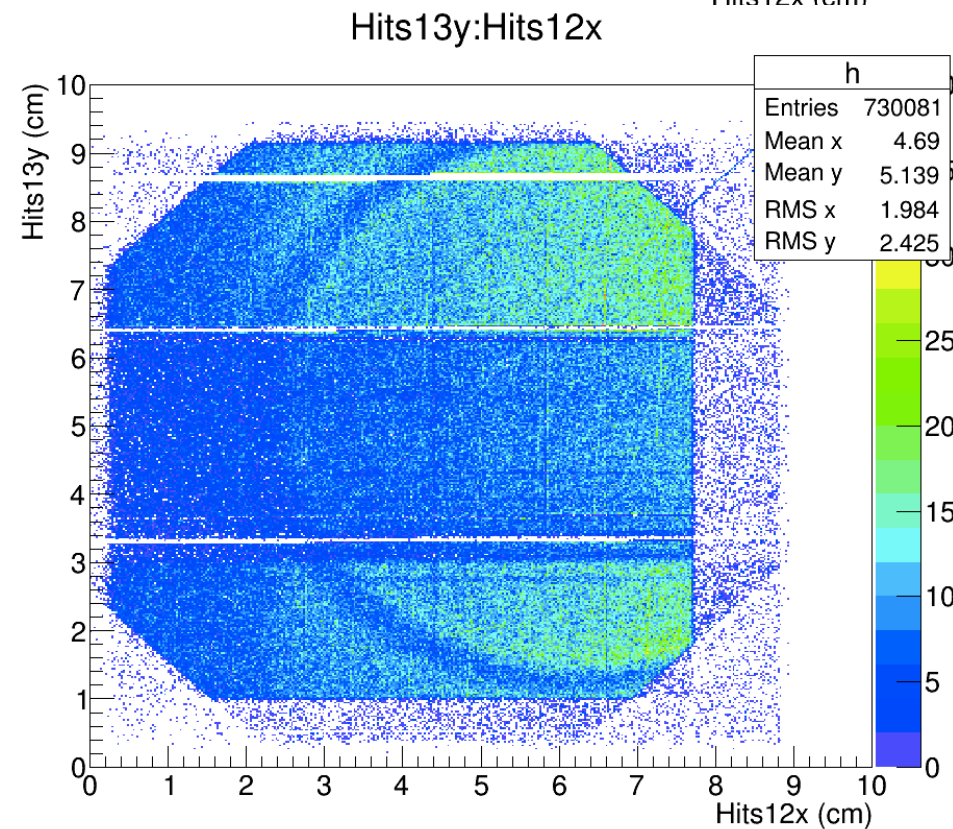
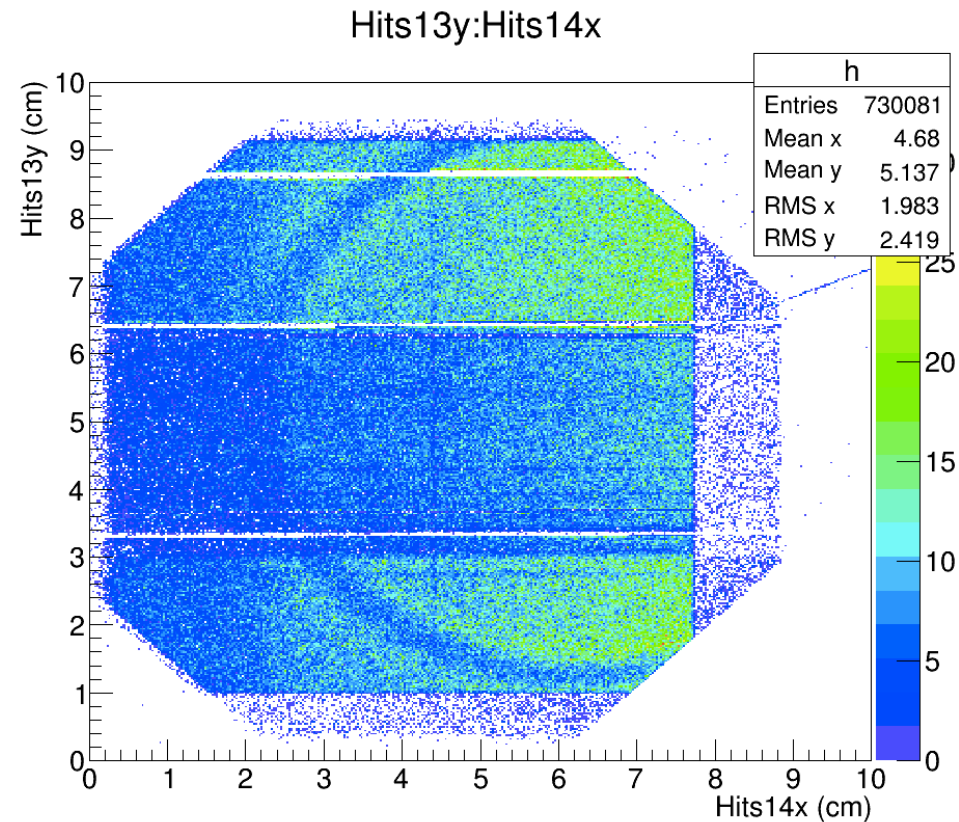
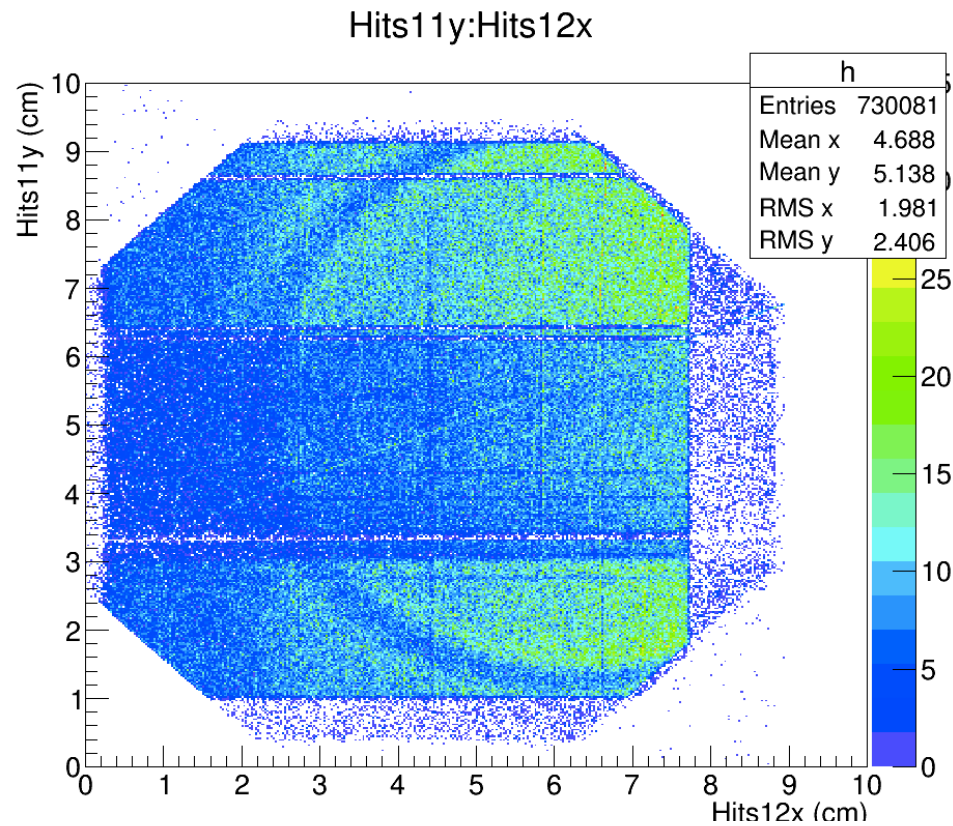
$$\implies a_i \text{ from } res_i \text{ vs } hits_j$$

$j = 13y$ for both !

Stereo planes rotations



11y 14x views



- Iteratively rotations of planes 11u / 14v

$$[11y] = \sqrt{2} [11u] - [12x] + (2 - \sqrt{2})c$$

$$[11y]' = [11y] - r_{11y} - a_{11y} \cdot [12x]$$

$$[14x] = \sqrt{2} [14v] + [13y] - \sqrt{2}c$$

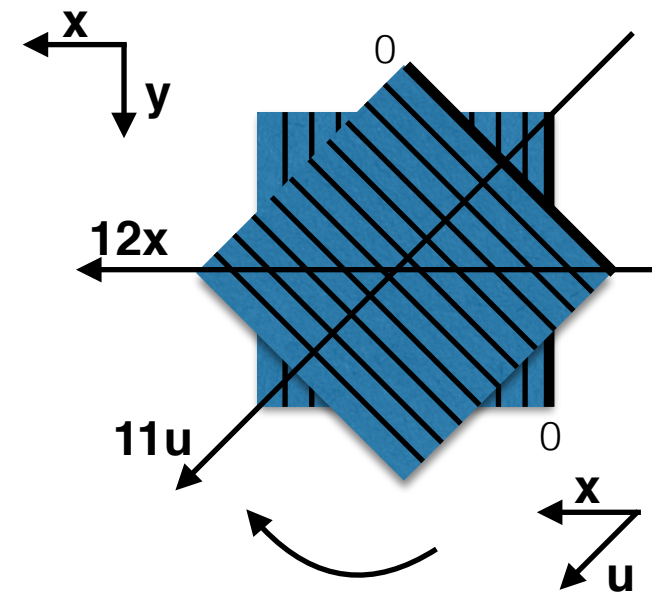
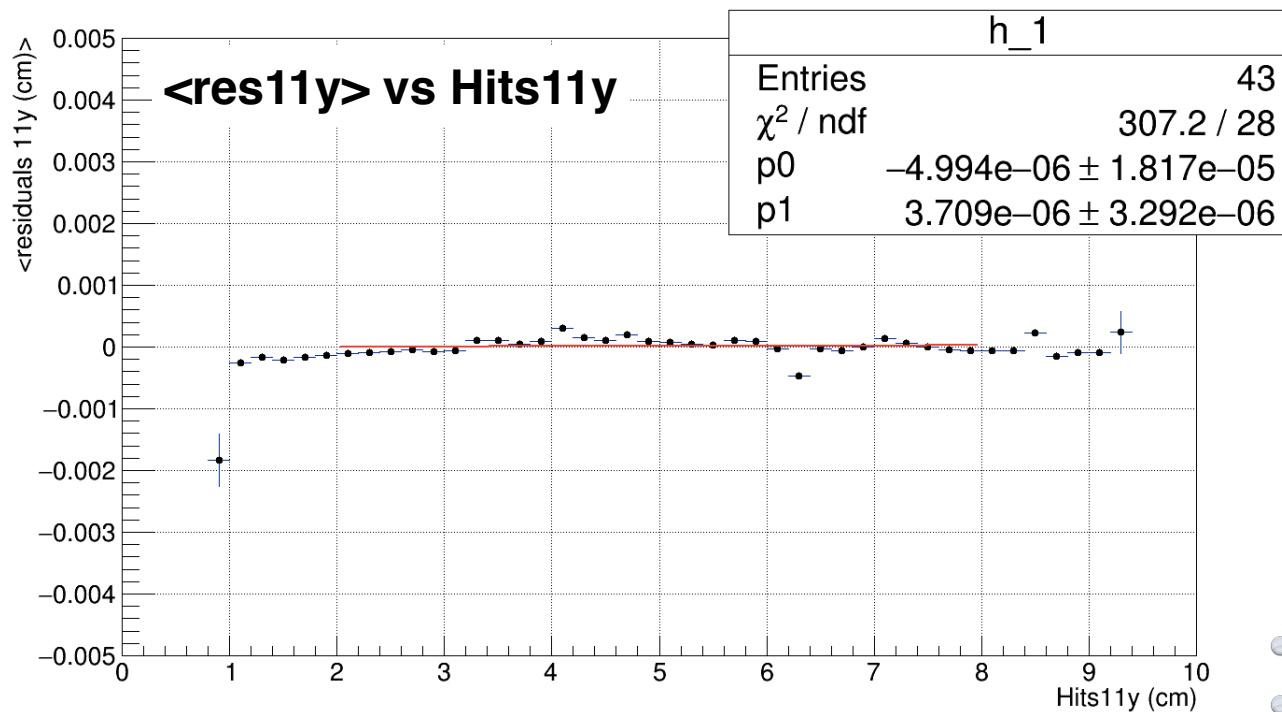
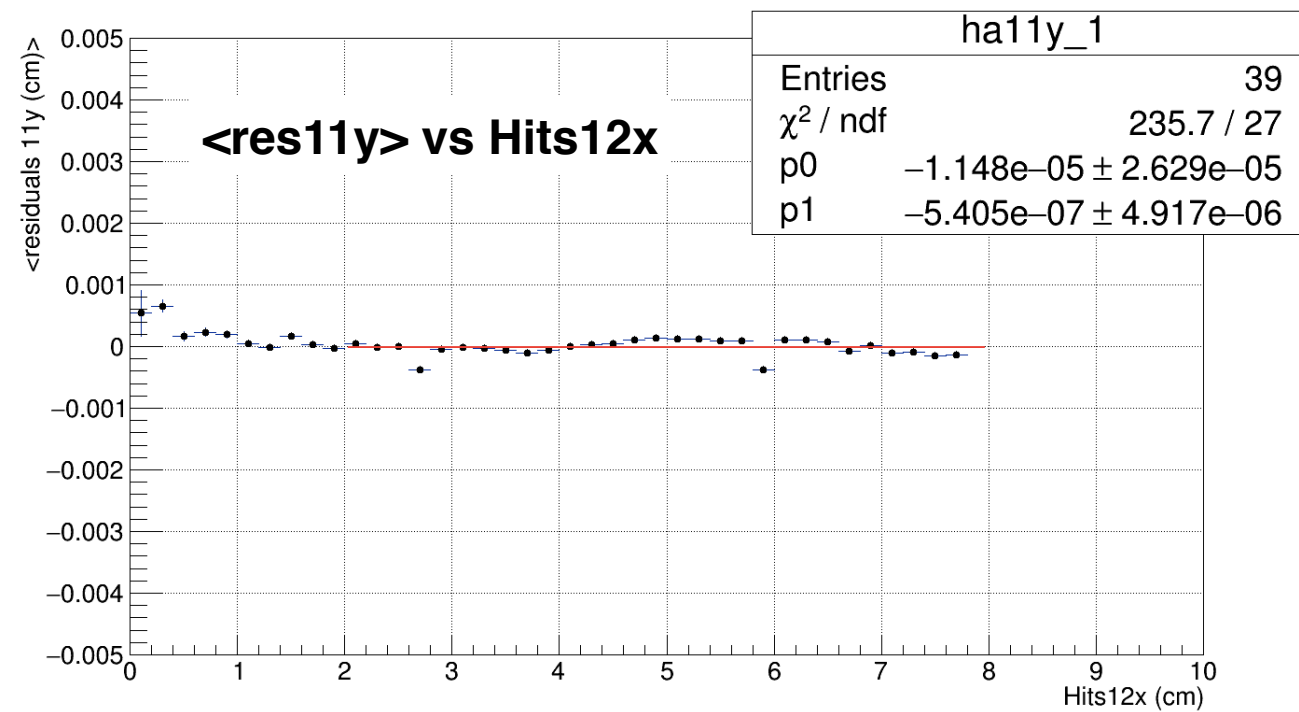
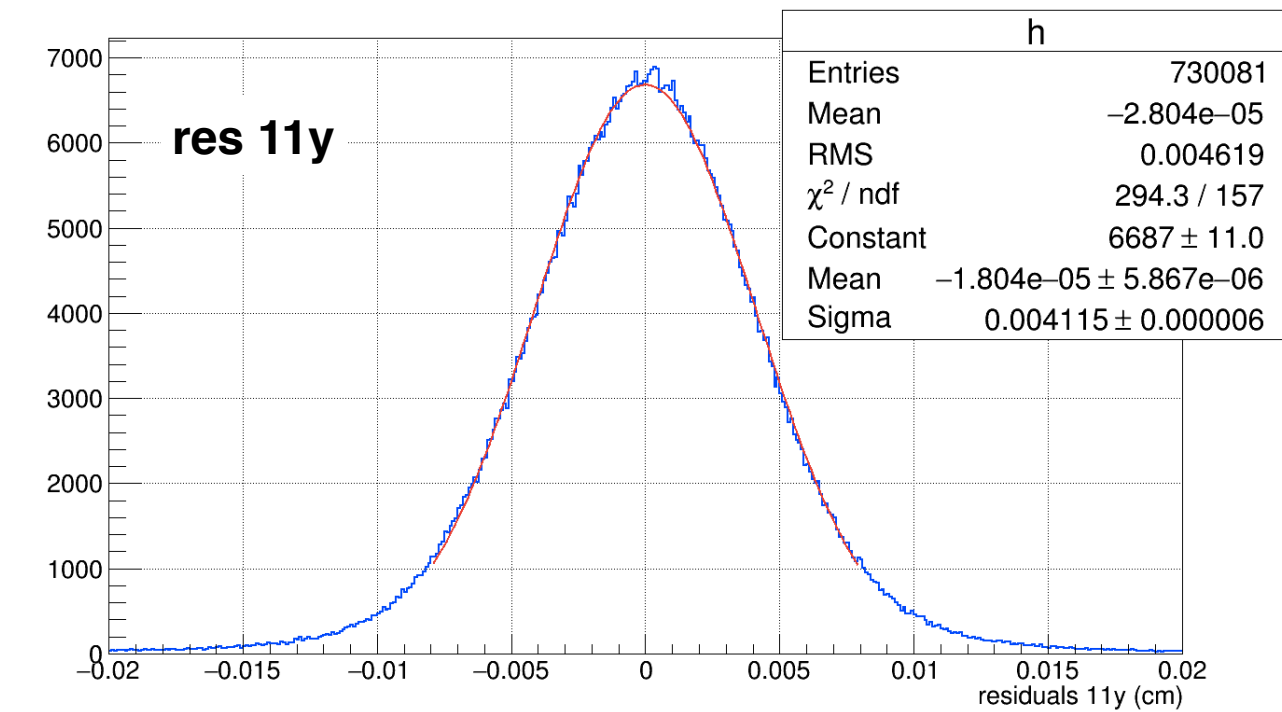
$$[14x]' = [14x] - r_{14x} - a_{14x} \cdot [13y]$$

$$c = 4.75 \text{ cm}$$

$$r_{11y} = 0.2328 \text{ cm} \quad a_{11y} = -0.00024 \text{ rad}$$

$$r_{14x} = 0.5081 \text{ cm} \quad a_{14x} = 0.00020 \text{ rad}$$

Alignment 11y



- Rotated hits (of 45°) becomes 11y.
- Obviously 11y residual has higher sigma than 11u:
27 μm \rightarrow 41 μm .

Final checks

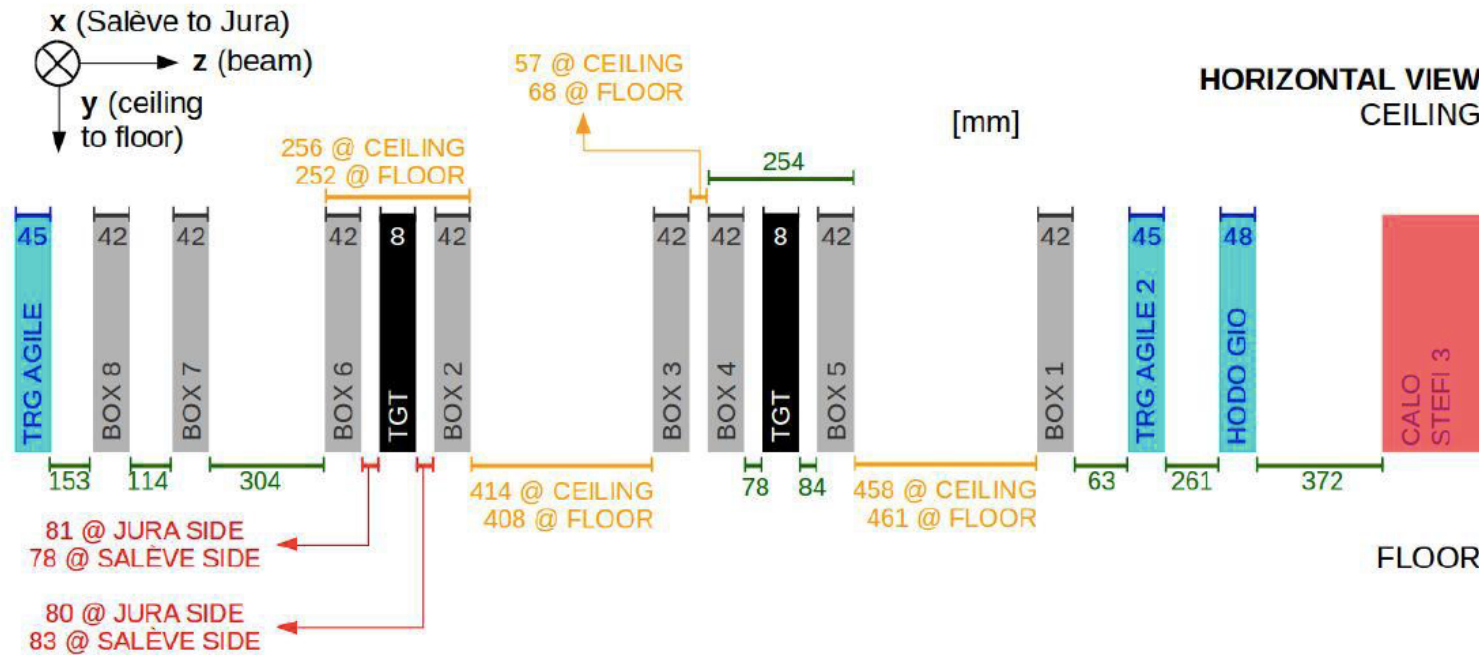
Layer resolution % bad hits

$\sigma_{residual}$	Cutted hits % (with mask)
1y 49 μm	1y ~34%
2x 38 μm	2x ~13%
3y 43 μm	3y ~6%
4x 40 μm	4x ~3%
5y 31 μm	5y ~19%
6x 32 μm	6x ~10%
7y 26 μm	7y ~7%
8x 25 μm	8x ~5%
9y 28 μm	9y ~4%
10x 40 μm	10x ~65%
11y 39 μm	11y ~1%
12x 25 μm	12x ~1%
13y 31 μm	13y ~8%
14x 41 μm	14x ~1%
15y 45 μm	15y ~5%
16x 48 μm	16x ~16%

- With a fit for all planes, we checked layer efficiencies, resolutions and also residual misalignments of planes chosen as a reference (5-6 and 15-16).
- Reference shifts in x / y: **within 1 μm** .
- Reference rotations along z axis within 0.1 mrad: more accurate checks would have been necessary.
- Anyway the choice of reference planes can introduce bias which can difficult to correct, especially if the misalignments are large, as in this case.

Conclusions

MUonE configuration @ 02/05



- z distances in cm.
- reference zero: bottom edge BOX 8

before 20/08 (in cm):

z(01)	-2.40	→ stereo (u)
z(02)	-0.30	
z(03)=	15.60 -2.50	
z(04)=	15.60 -0.50	
z(05)=	50.00 -2.50	
z(06)=	50.00 -0.50	
z(07)=	71.40 -1.50	
z(08)=	71.40 -0.33	
z(09)=	117.00 -2.50	
z(10)=	117.00 -0.50	
z(11)=	126.90 -1.83	→ stereo (u)
z(12)=	126.90 -0.50	
z(13)=	148.10 -0.34	
z(14)=	148.10 -1.56	→ stereo (v)
z(15)=	198.10 -1.00	
z(16)=	198.10 -2.30	

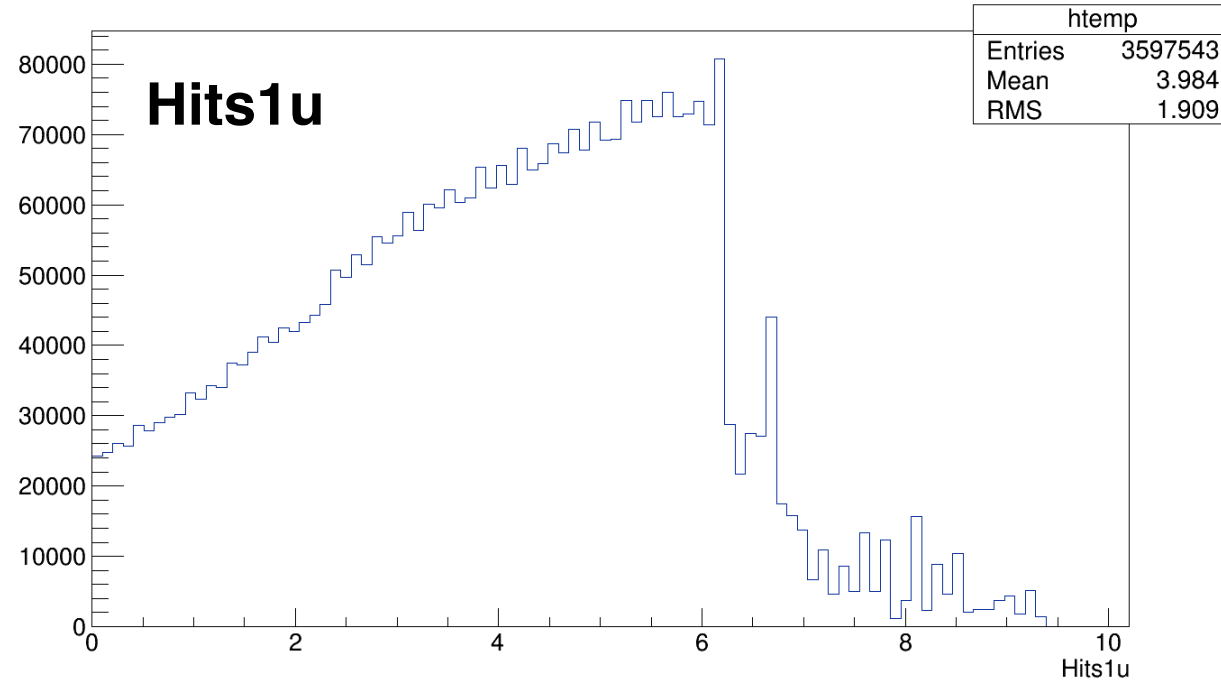
-2 mm!

- from 4/05: 3 upstream boxes
- from 27/06: no target 2
- from 20/08: new box 8 and 3
- Provided distances up to 20/08 contain an error:
-2 mm for layers 1 - 2 - 3 - 4.
- I only checked the effect on tracking a posteriori, without re-aligning all samples uploaded on eos.

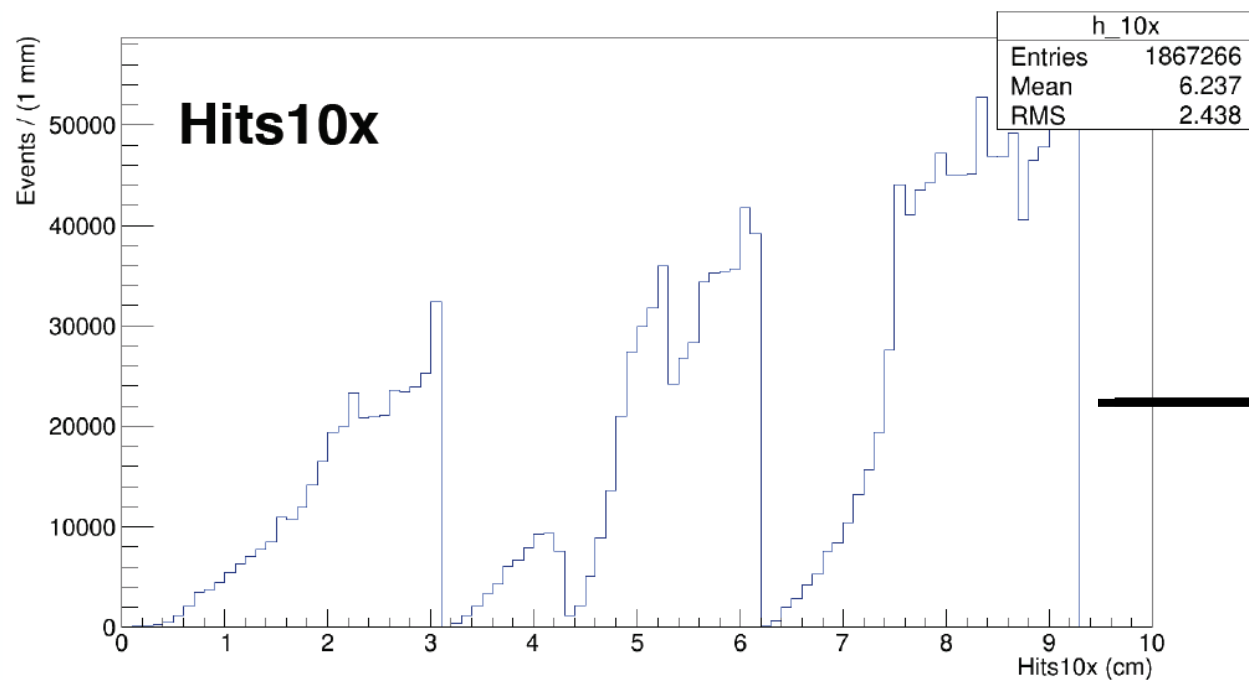
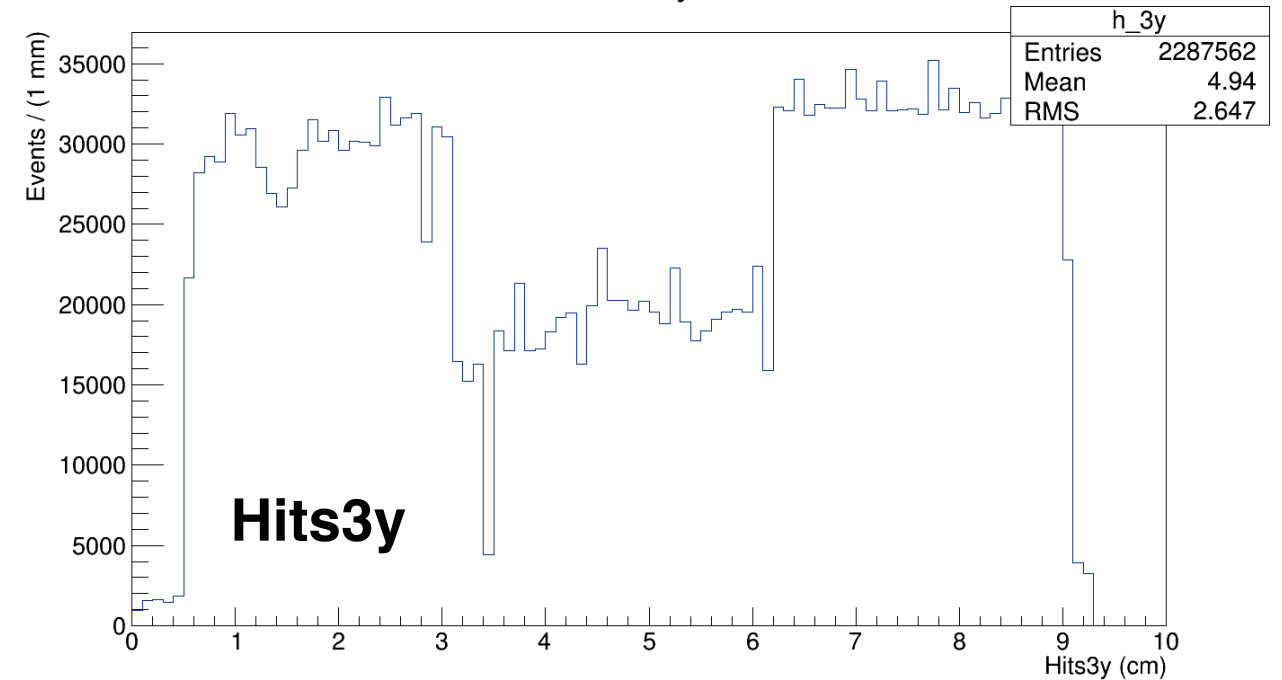
Backup

Layer problems: some examples

Hits1u {Hits1u<10.}

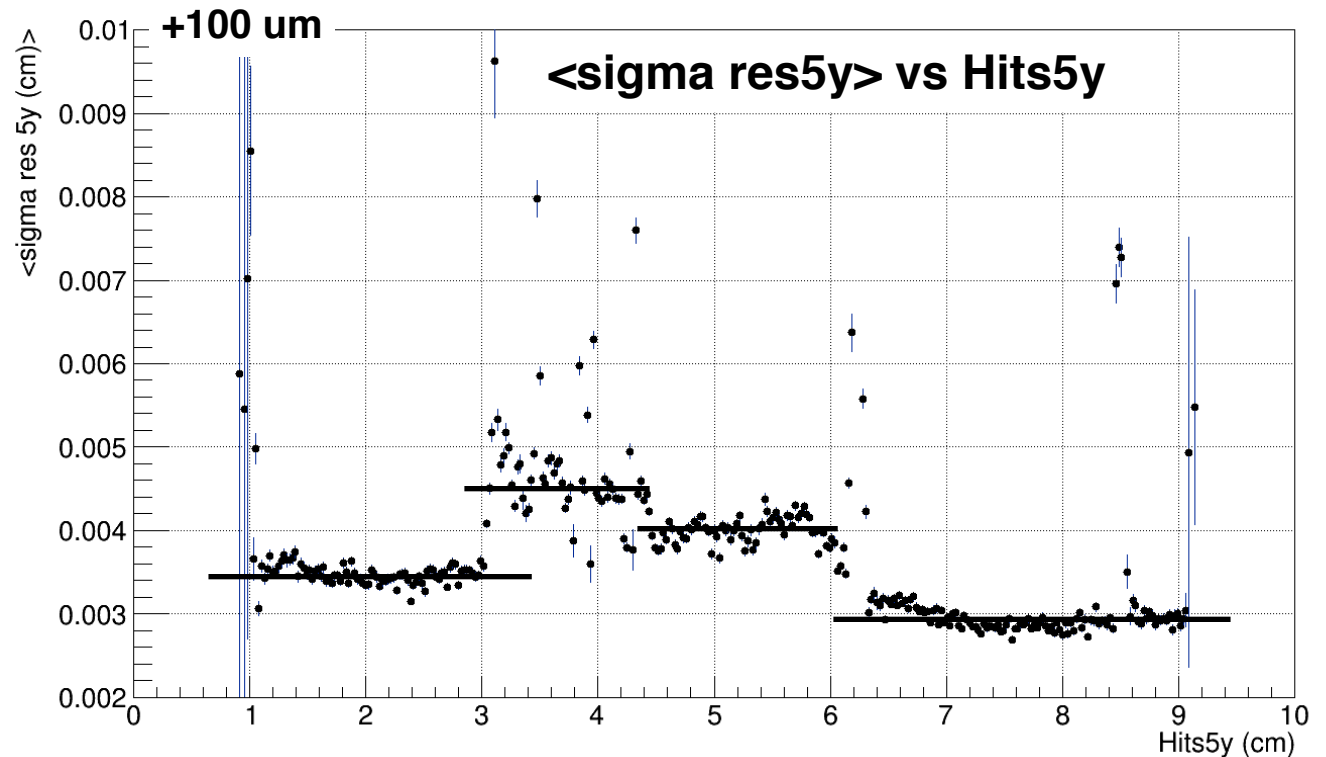
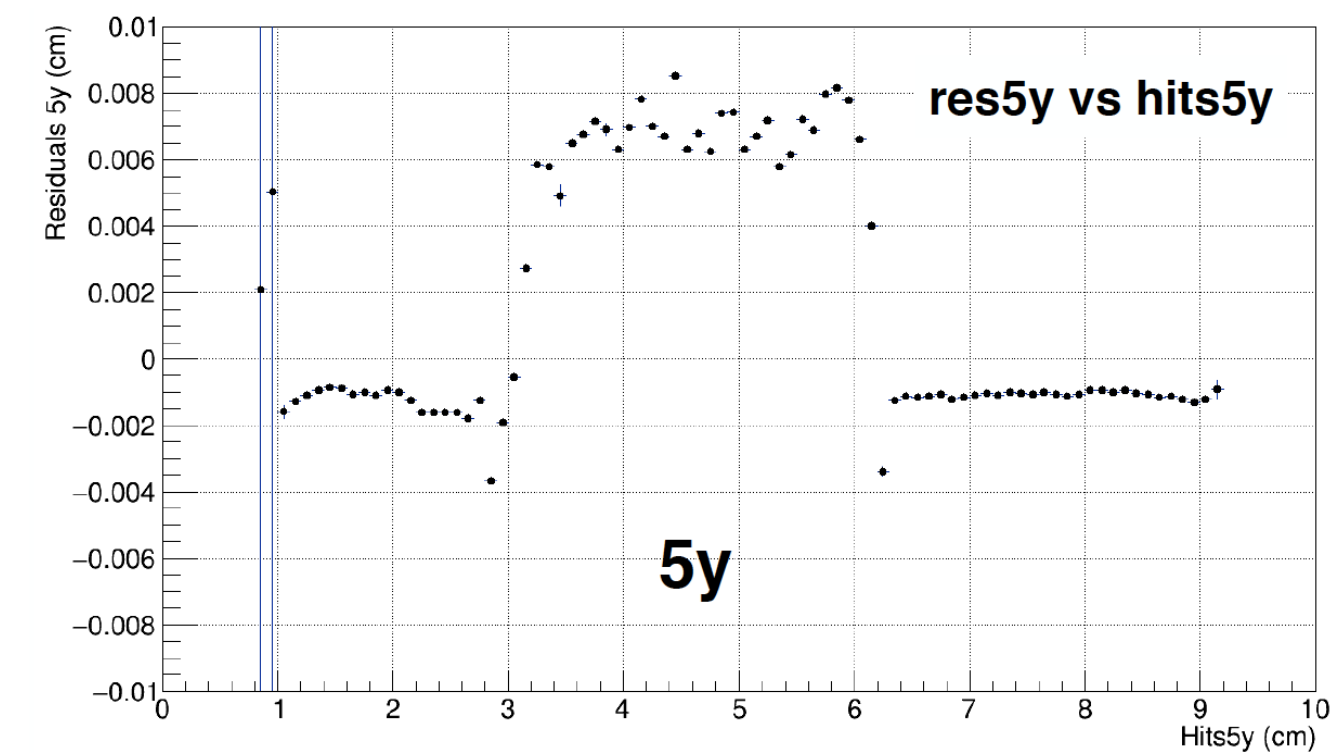
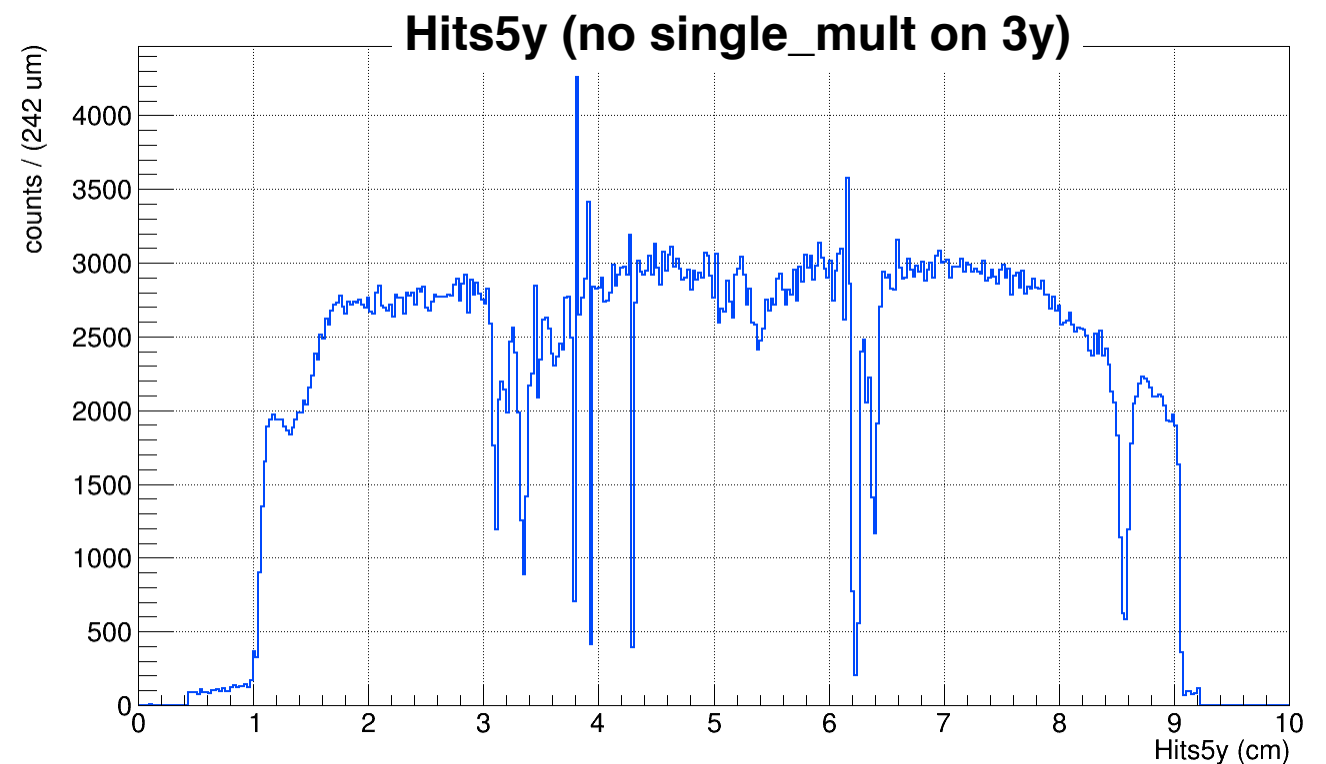
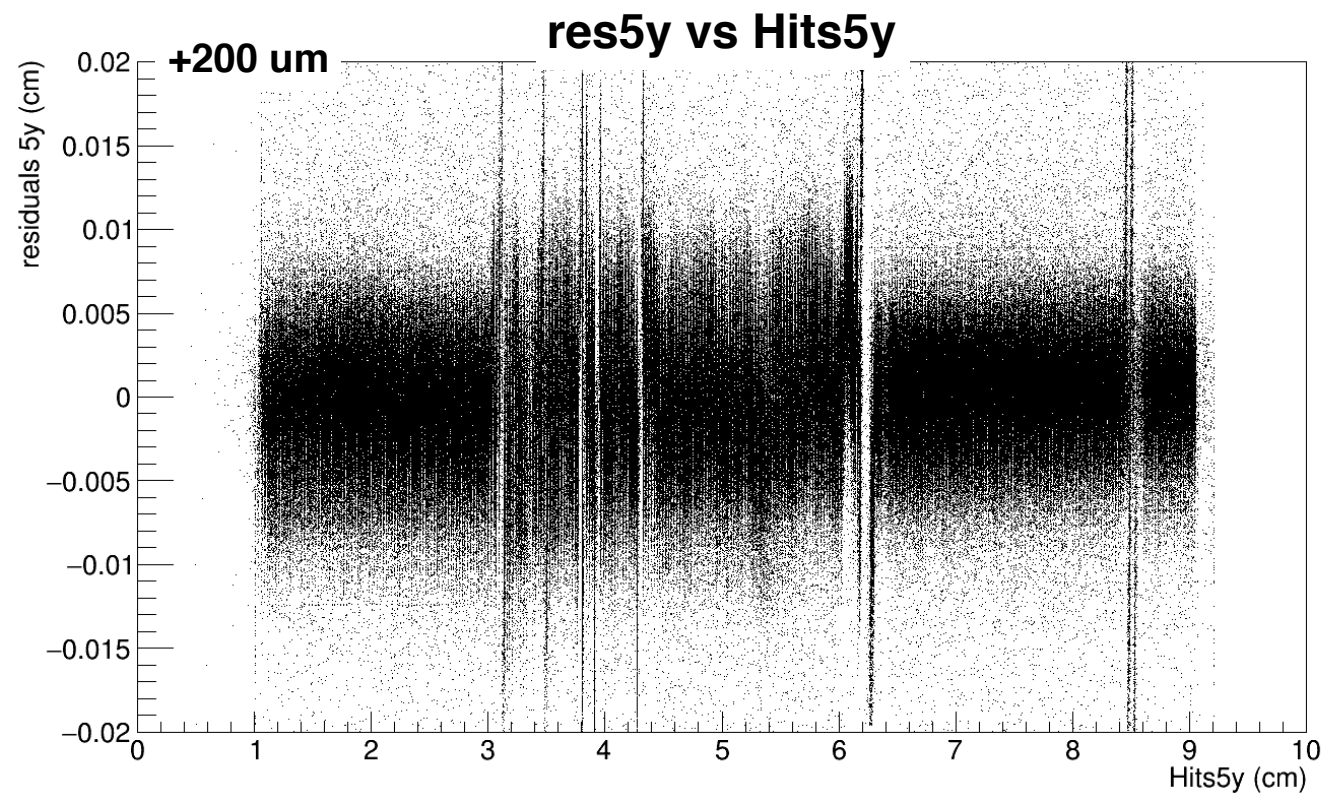


Hits3y



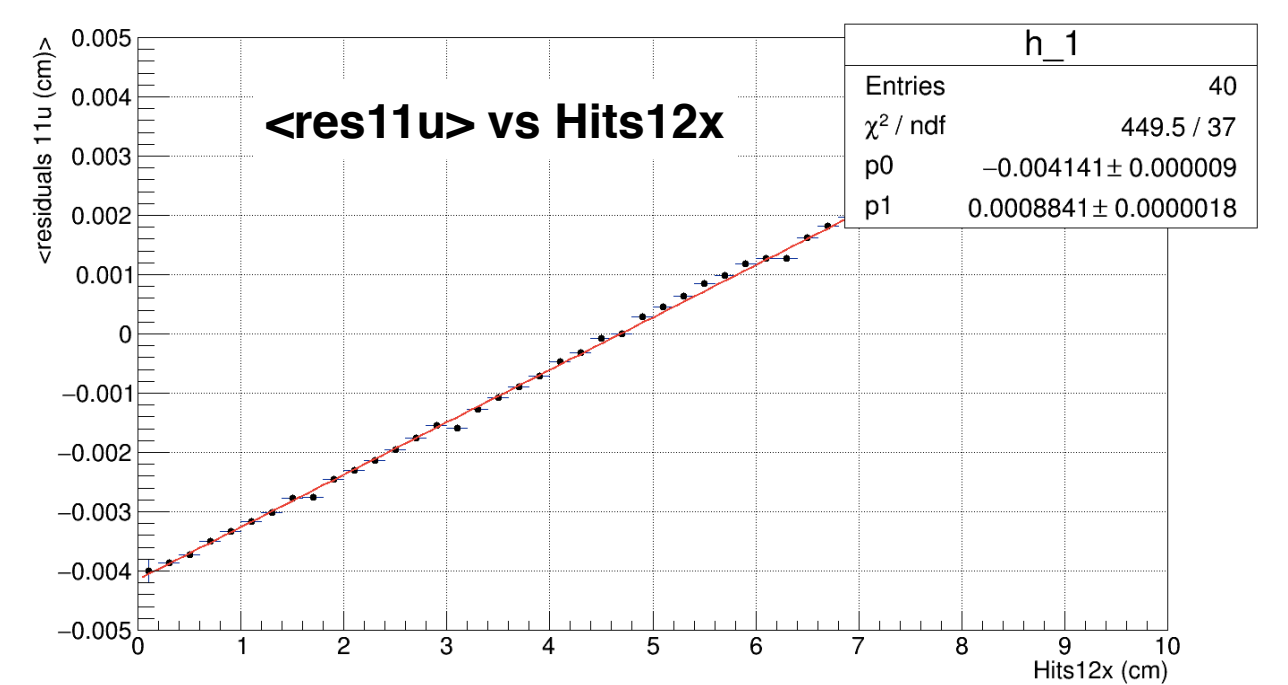
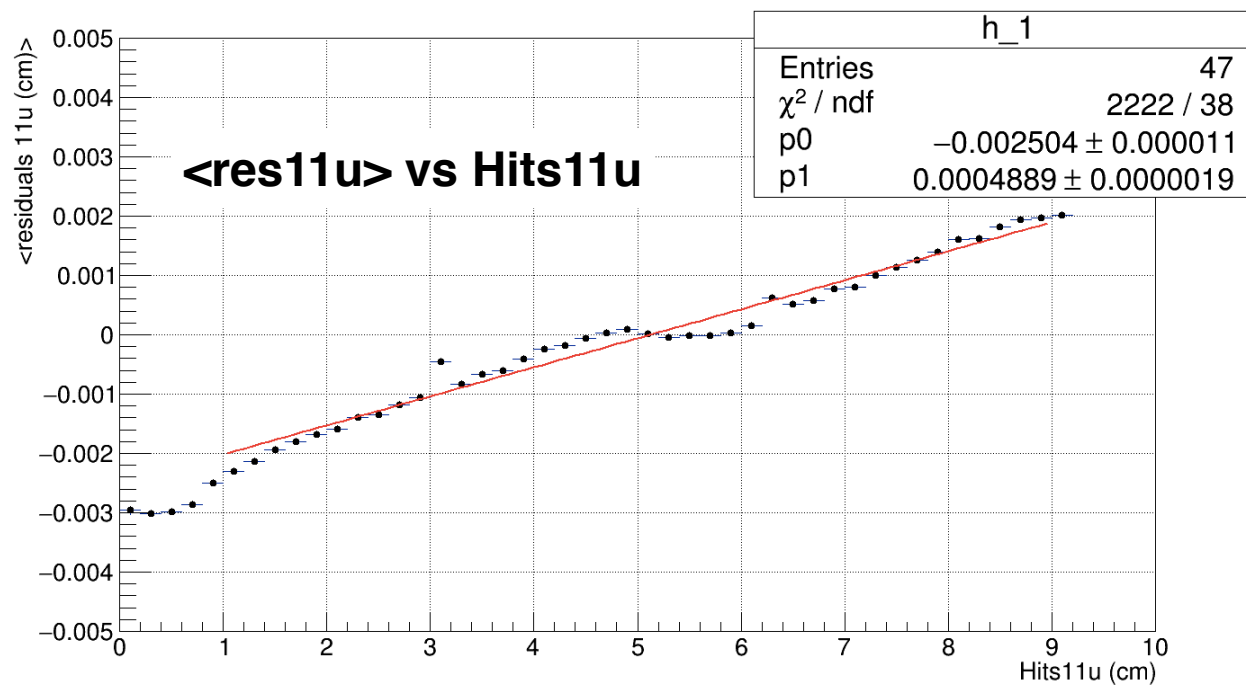
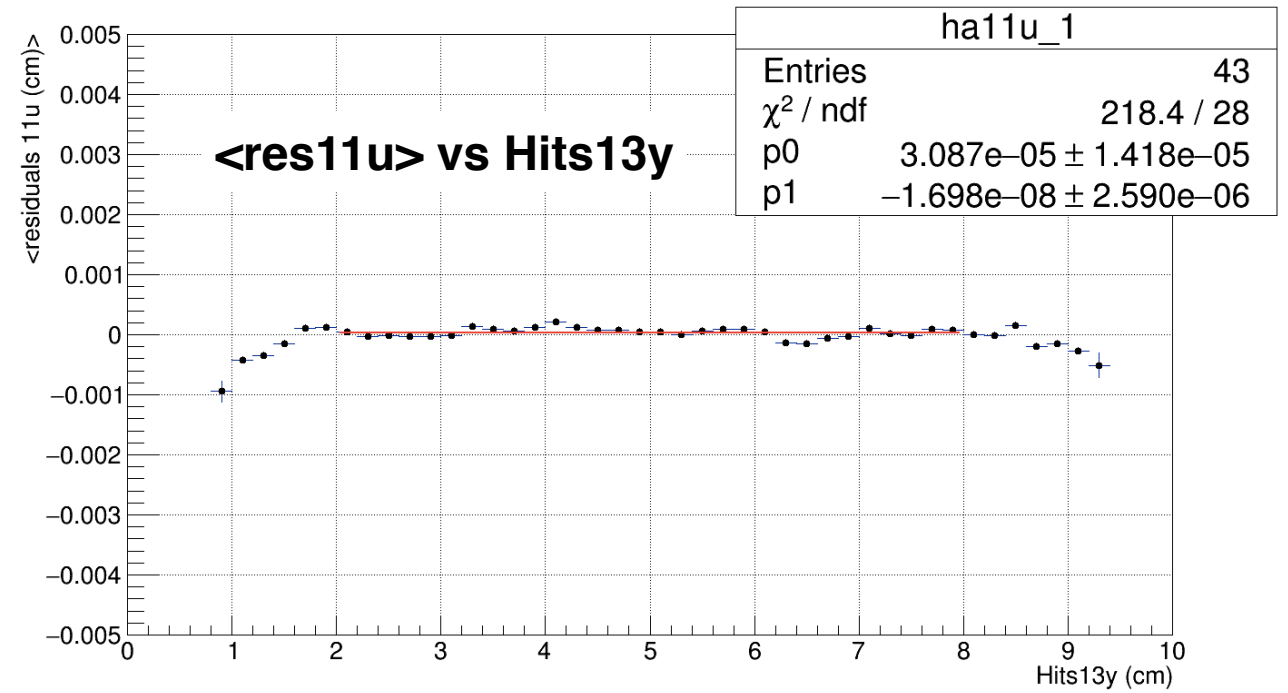
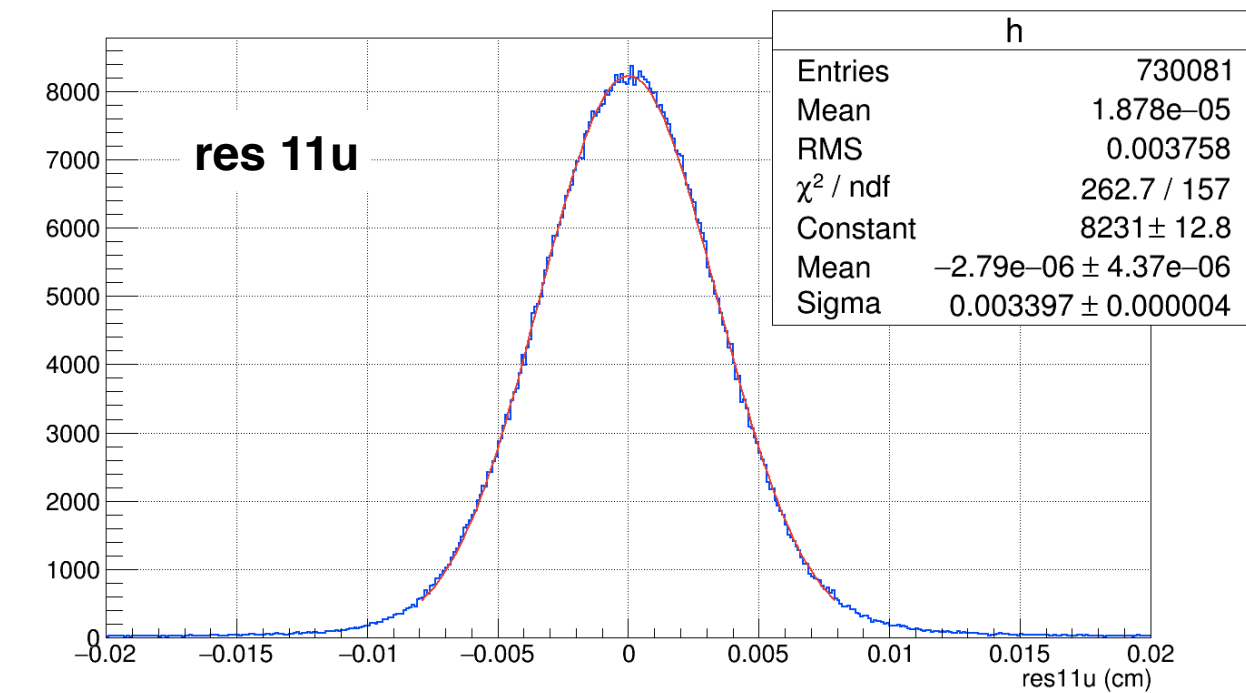
- Almost all layers show inefficiency problems: it's very clear the ASIC structure.
- In the next slides a quantitative efficiency analysis.
- We've correlated some of these problems with the high beam intensity relatively to the apparatus readout.
- Layers 1u and 10x have been changed at the end of August (test beam is running from May).
- In these slides new setup (new boxes) are not shown.

Layer problems: plane 5y



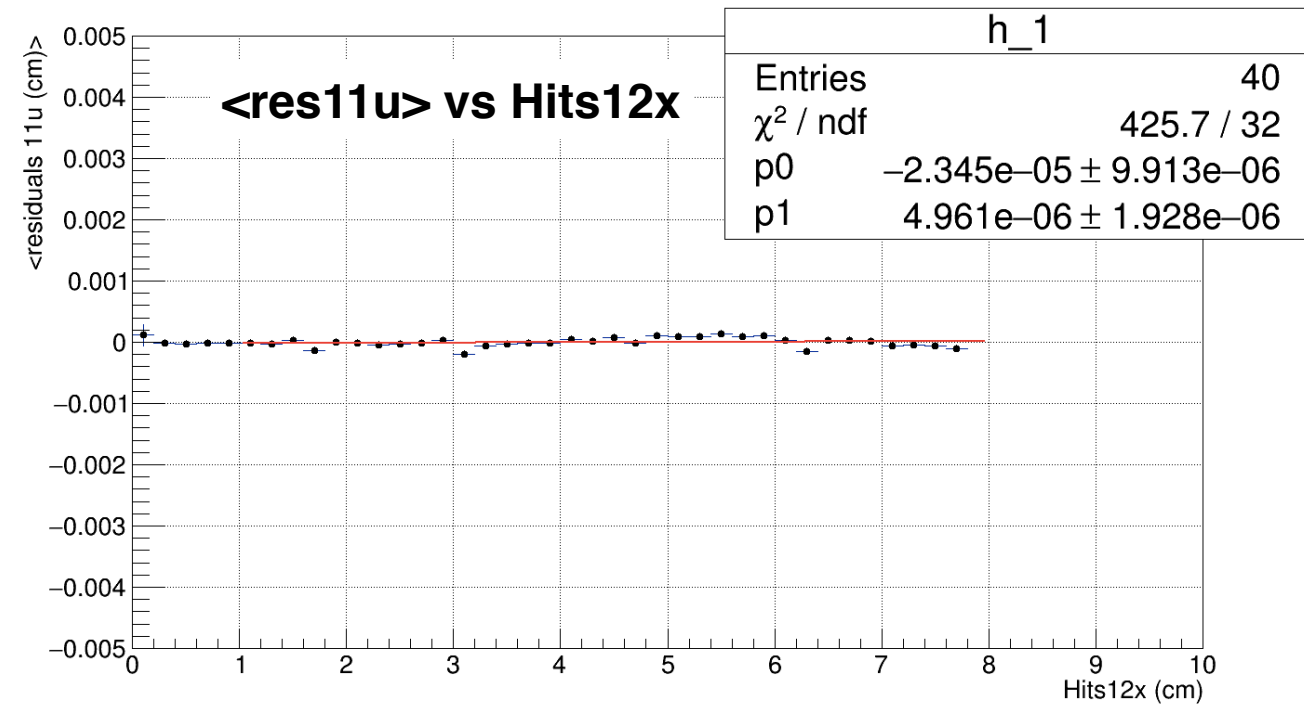
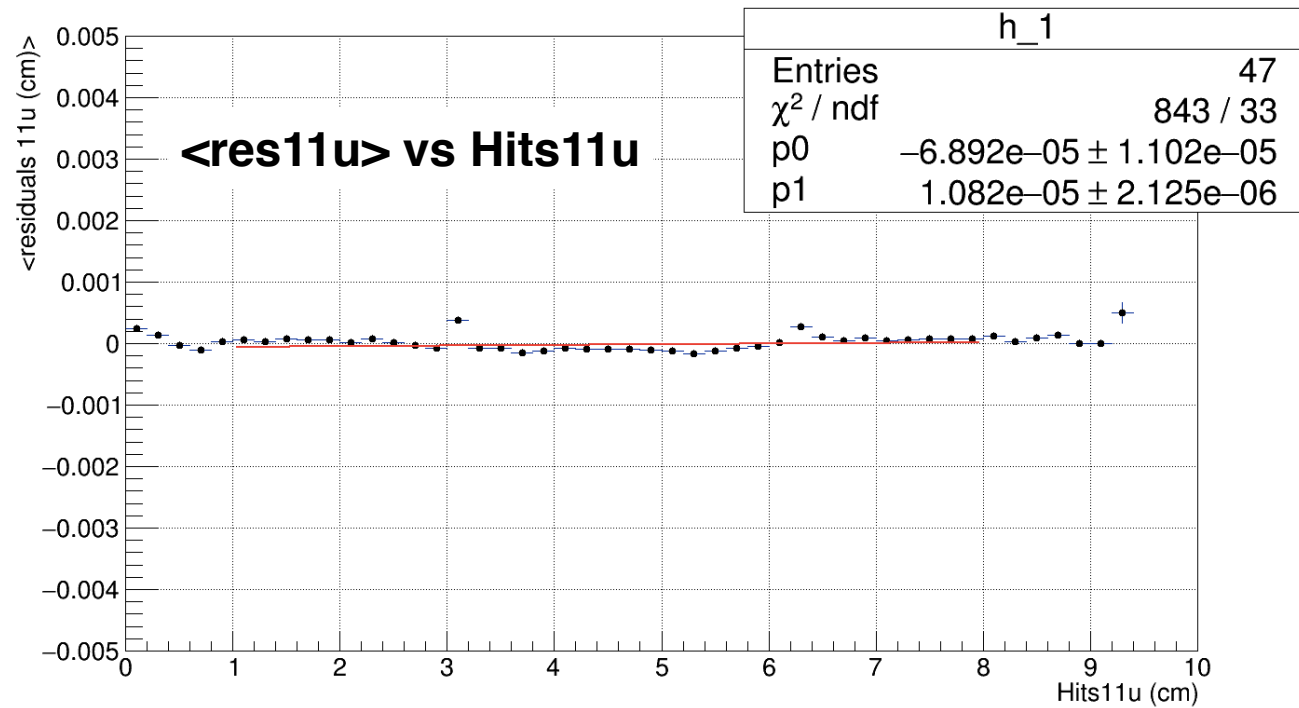
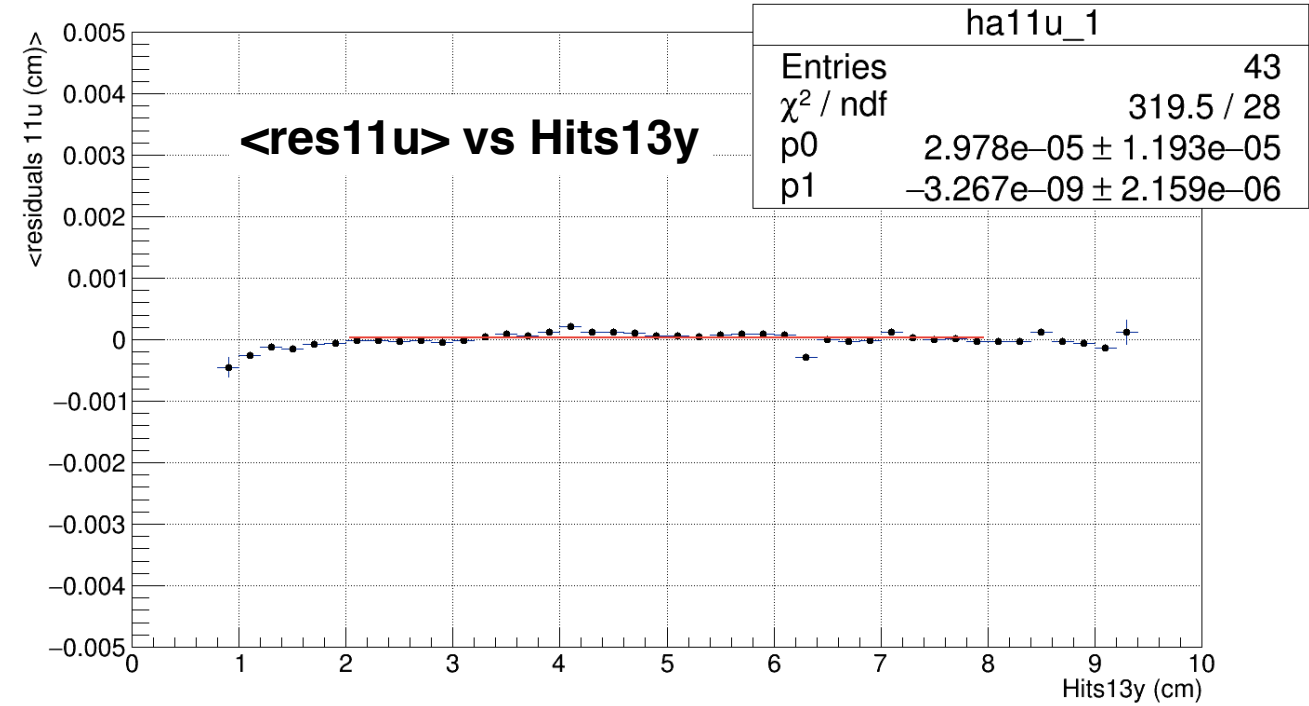
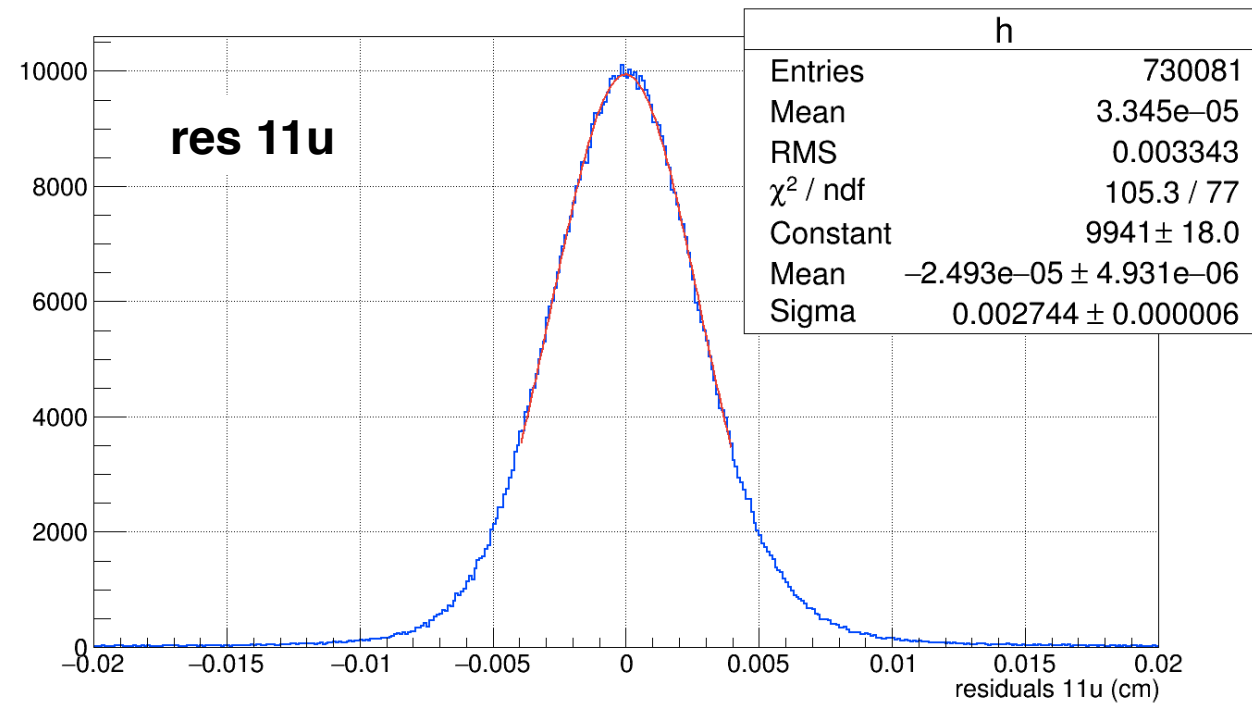
- Situation of 5y trackers (upstream) **pre-correction**: noisy behavior and shift of central ASIC. Also the resolution at the center is significantly different (sigmas plot).
- As other planes, many dead strips which induce a bad reco of nearest strips.

Alignment 11u pre tilt correction



- Correlation (tilt-like) between res11u and hits11u, induces a correlations res11u vs hits12x, which appears like a relative rotation. Correction: **Hits11u' = (1-0.001244)*Hits11u**. It's not possible to apply it iteratively.

Alignment 11u post correction



- **Hits11u' = (1-0.001244)*Hits11u.** The residual and other correlations improve significantly: 34 μm \rightarrow 27 μm .

Efficiencies analysis: hit / event

Layer resolution		% bad hits	Hit eff	
$\sigma_{residual}$		Cuttet hits % (with mask)	$\epsilon_{3.28\sigma}$ $\chi_x^2 + \chi_y^2 < 26$ (only chi2, <u>no mask</u>)	
1y	49 μm	1y ~34%	1y	94.6%
2x	38 μm	2x ~13%	2x	95.1%
3y	43 μm	3y ~6%	3y	73.9%
4x	40 μm	4x ~3%	4x	76.8%
5y	31 μm	5y ~19%	5y	98.6%
6x	32 μm	6x ~10%	6x	98.8%
7y	26 μm	7y ~7%	7y	96.1%
8x	25 μm	8x ~5%	8x	96.7%
9y	28 μm	9y ~4%	9y	59.9%
10x	40 μm	10x ~65%	10x	59.2%
11y	39 μm	11y ~1%	11y	98.2%
12x	25 μm	12x ~1%	12x	98.4%
13y	31 μm	13y ~8%	13y	94.8%
14x	41 μm	14x ~1%	14x	94.3%
15y	45 μm	15y ~5%	15y	82.1%
16x	48 μm	16x ~16%	16x	83.4%

Event efficiencies downstream planes

7y	67.5%
8x	54.4%
9y	78.2%
10x	25.0%
11u	81.3%
12x	88.6%
13y	83.8%
14v	79.5%
15y	80.6%
16x	85.2%

4 runs only T1

2x-3y-4x-5y-6x (m==1)

11111 T: 18.4e+06 incoming muons

• Taking in coincidence 3 best layers per view:
(11u-12x-13y-14v-15y-16x)

0.81*0.89*0.84*0.80*0.81*0.85 ~ 33%
(best event eff)

• With the worst:
(7y-8x-9y-10x-15y-16x)

0.68*0.54*0.78*0.25*0.81*0.85 ~ 5%
(worst event eff)